



# Beam Instrumentation and Diagnostics (Lecture 1)

## CAS 2019

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# Introduction

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- **What do we mean by beam instrumentation?**
  - The “eyes” of the machine operators
    - i.e. the instruments that observe beam behaviour
    - An accelerator can never be better than the instruments measuring its performance!
- **What does work in beam instrumentation entail?**
  - Design, construction & operation of instruments to observe particle beams
  - R&D to find new or improve existing techniques to fulfill new requirements
  - A combination of the following disciplines
    - Applied & Accelerator Physics; Mechanical, Electronic & Software Engineering
- **What beam parameters do we measure?**
  - Beam Position
    - Horizontal and vertical throughout the accelerator
    - At a specific location for tune, coupling & chromaticity measurements
  - Beam Intensity (& lifetime measurement for a storage ring/collider)
    - Bunch-by-bunch charge and total circulating current
  - Beam Loss
    - Especially important for high brightness and superconducting machines
  - Beam profiles
    - Transverse and longitudinal distribution



# What is meant by Beam Diagnostics?


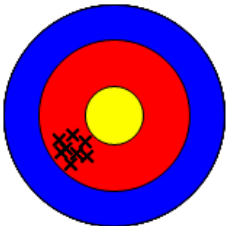

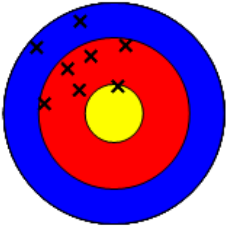
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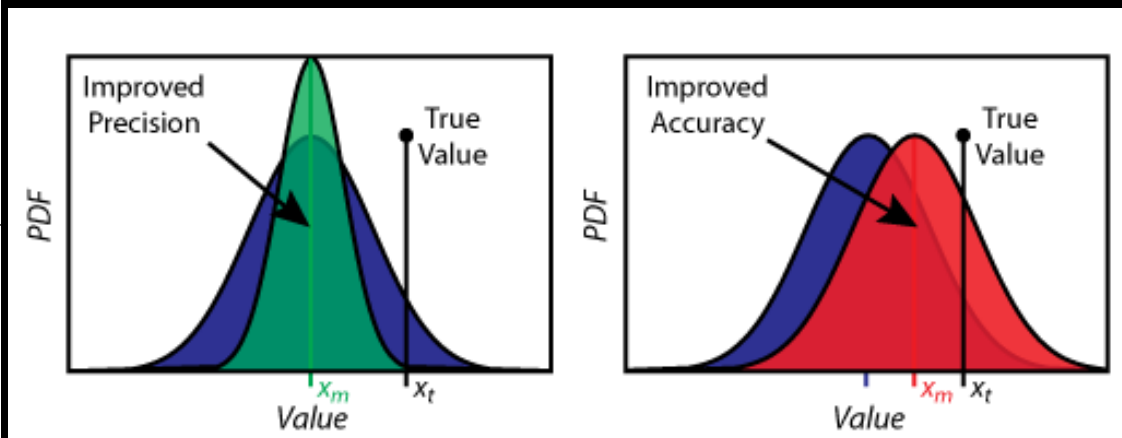
- **Beam Diagnostics**
  - Making use of beam instrumentation
- **What do we consider as beam diagnostics?**
  - Operating the accelerators
    - Using instrumentation to measure and correct standard parameters
      - Orbit, tune, chromaticity control etc.
  - Improving the performance of the accelerators
    - Understanding current performance to allow future improvements
    - Requires the measurement of performance indicators
      - Luminosity, brilliance (intensity and size) etc.
  - Understanding accelerator limitations
    - Beam loss, instabilities, emittance growth etc.
  - Detecting equipment faults
    - Aperture restrictions, polarity inversions, wrong settings etc.

# How do we Qualify Beam Measurements?

- Accuracy, Precision, Resolution

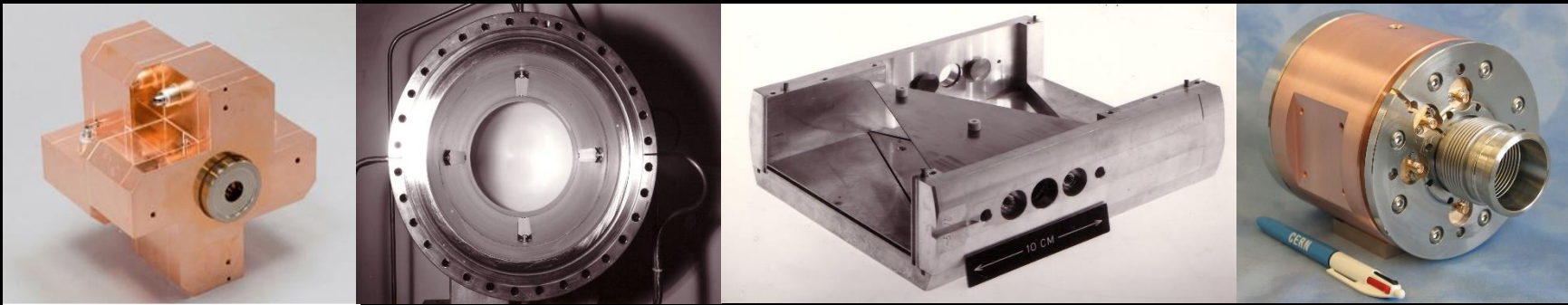
- Very often confused in day-to-day language
  - Accuracy – also known as the trueness of a measurement
  - Precision – how well a measurement can be reproduced
  - Resolution – the smallest possible difference measurable

	Accurate	Inaccurate (systematic error)
Precise		
Imprecise (reproducibility error)		



- Example for a BPM

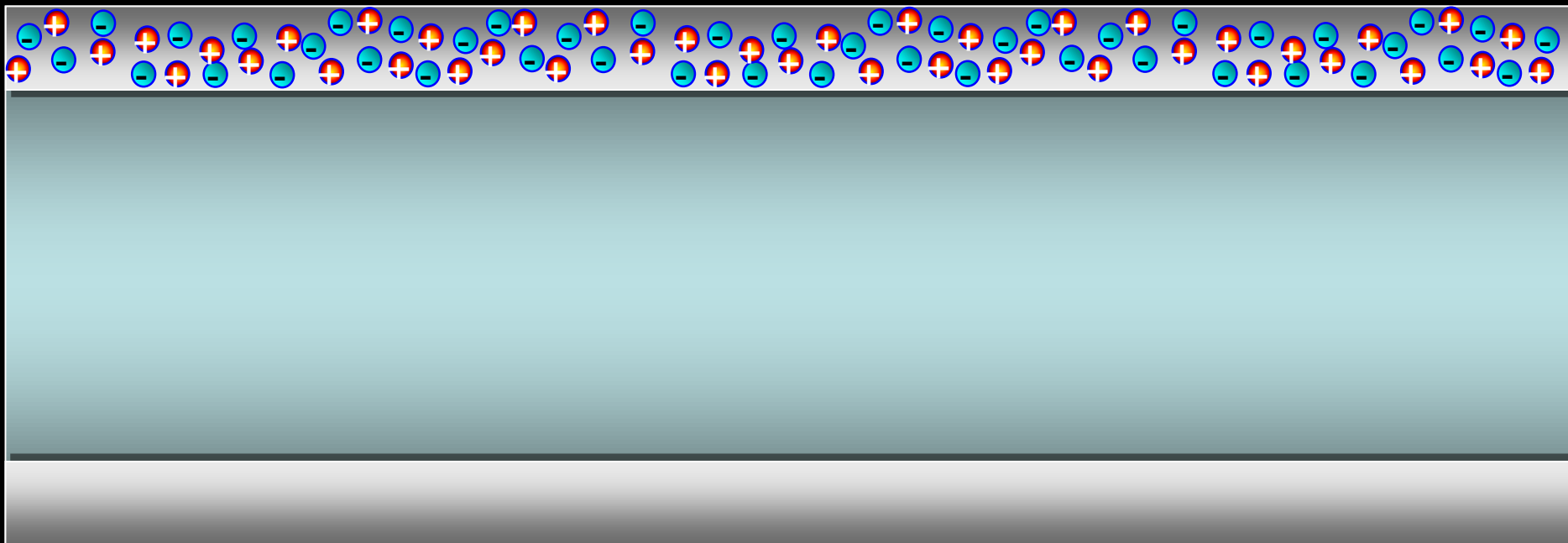
- Mechanical & electrical offsets and gain factors influence accuracy
- Various noise sources or timing jitter influence the precision
- Number of bits in the ADC will limit the resolution



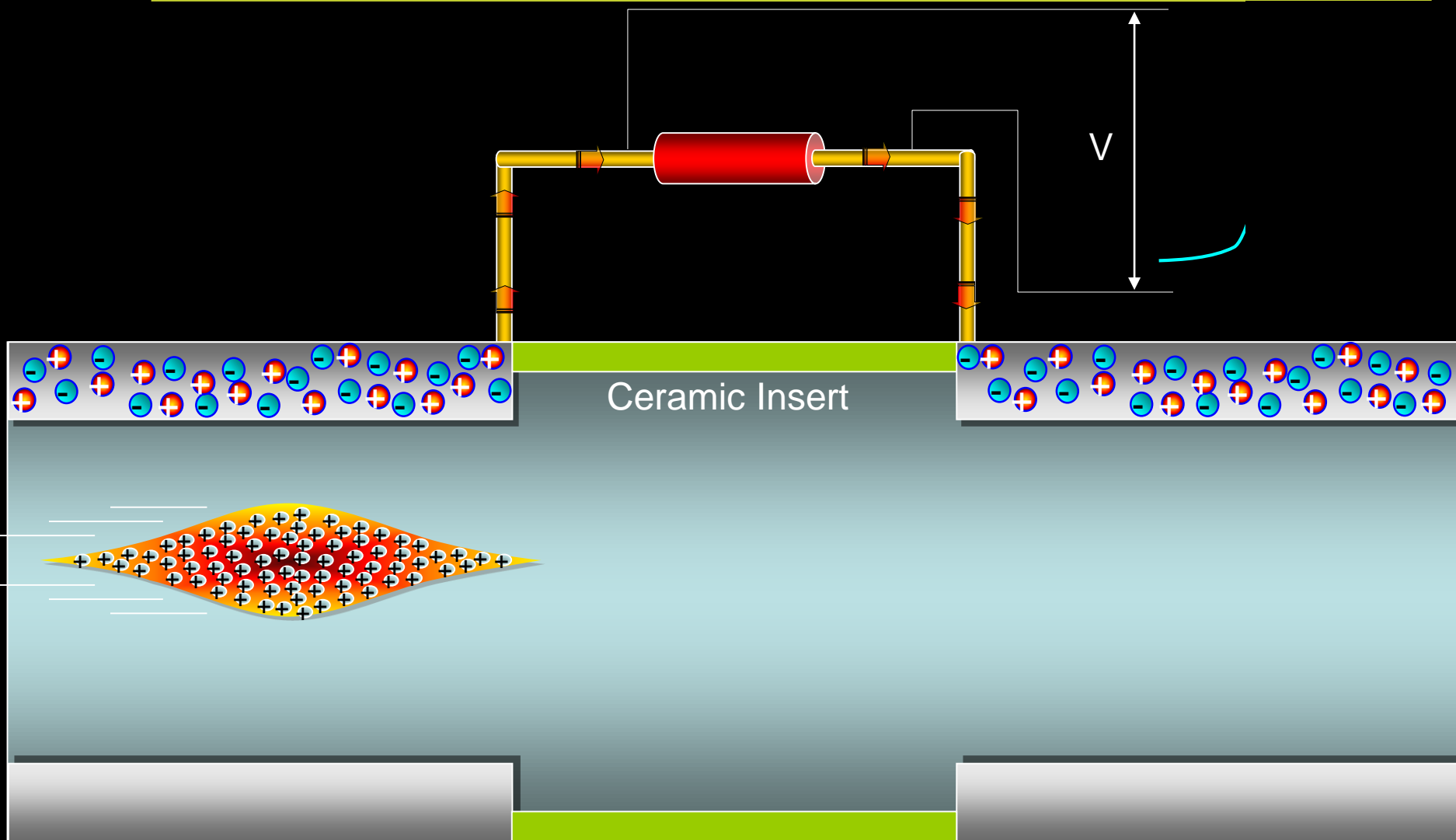
# Beam Position Systems

# Measuring Beam Position – The Principle

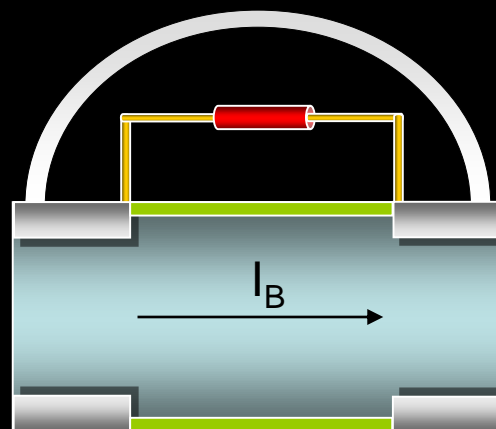
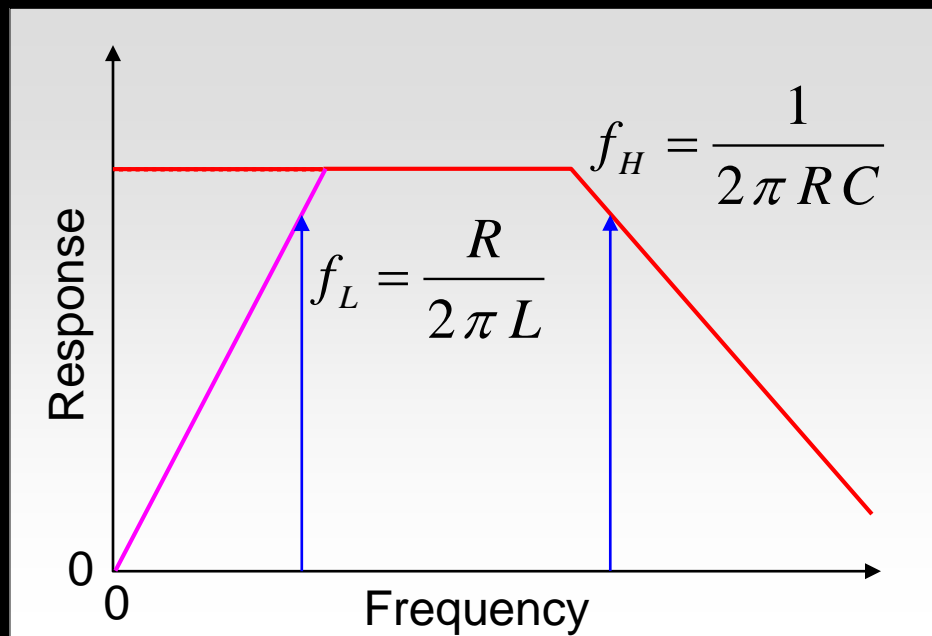
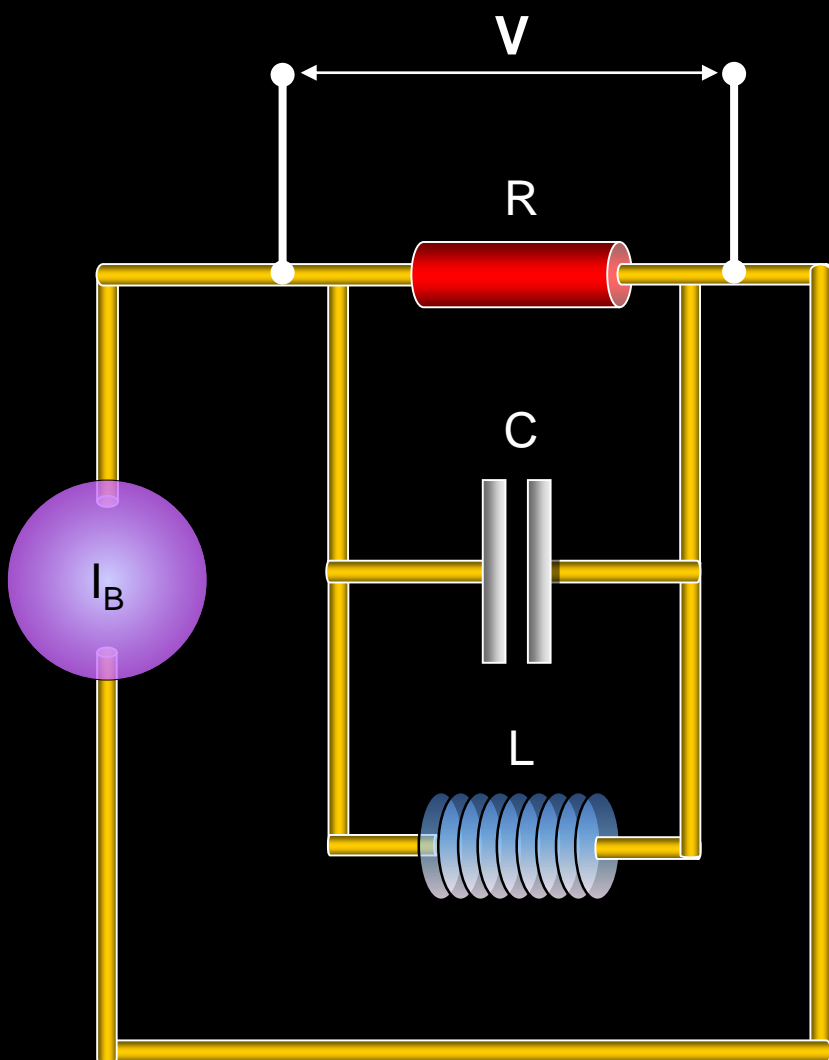
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# Wall Current Monitor – The Principle

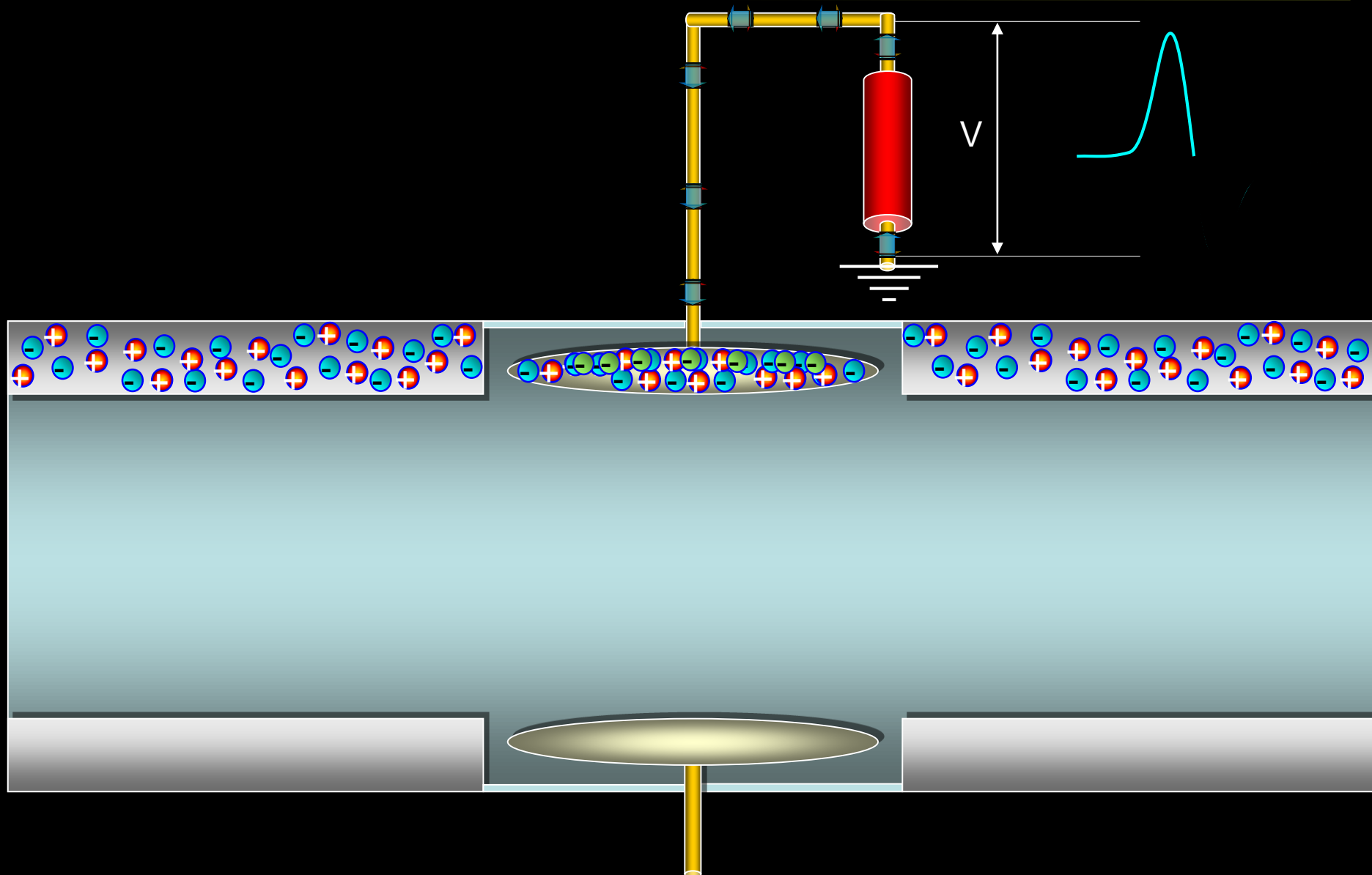


# Wall Current Monitor – Beam Response

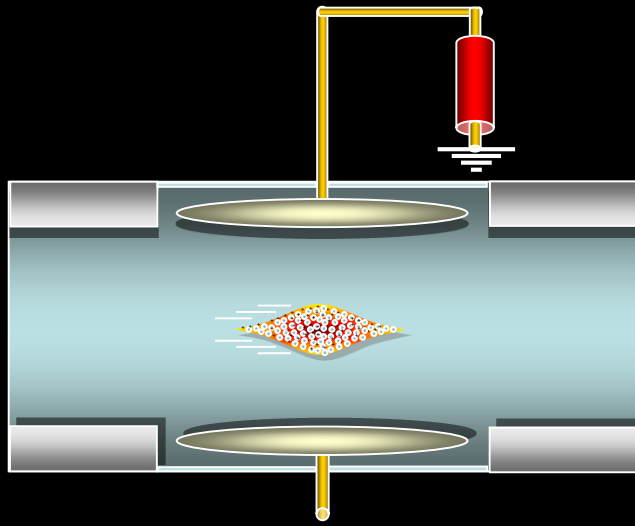
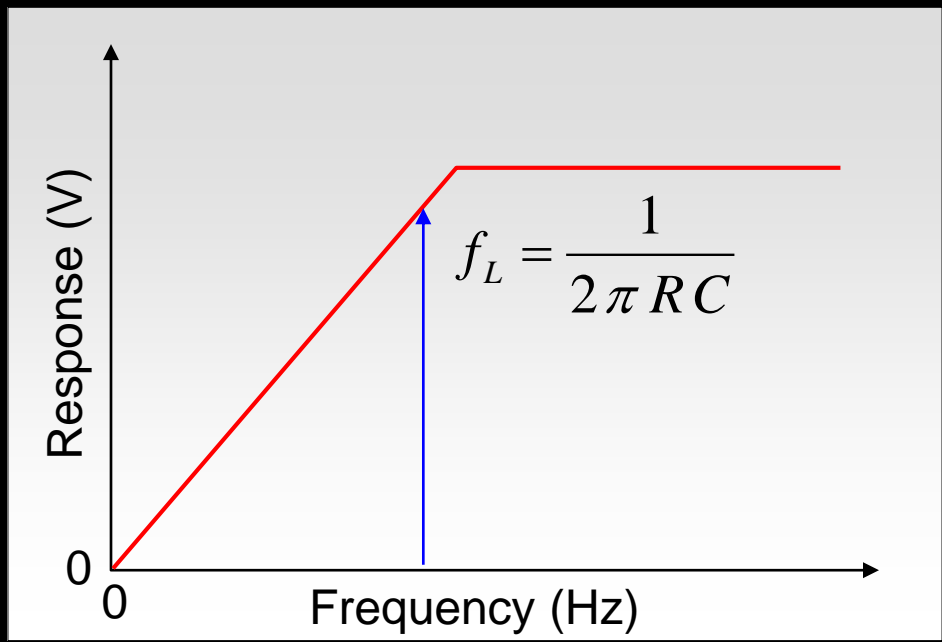
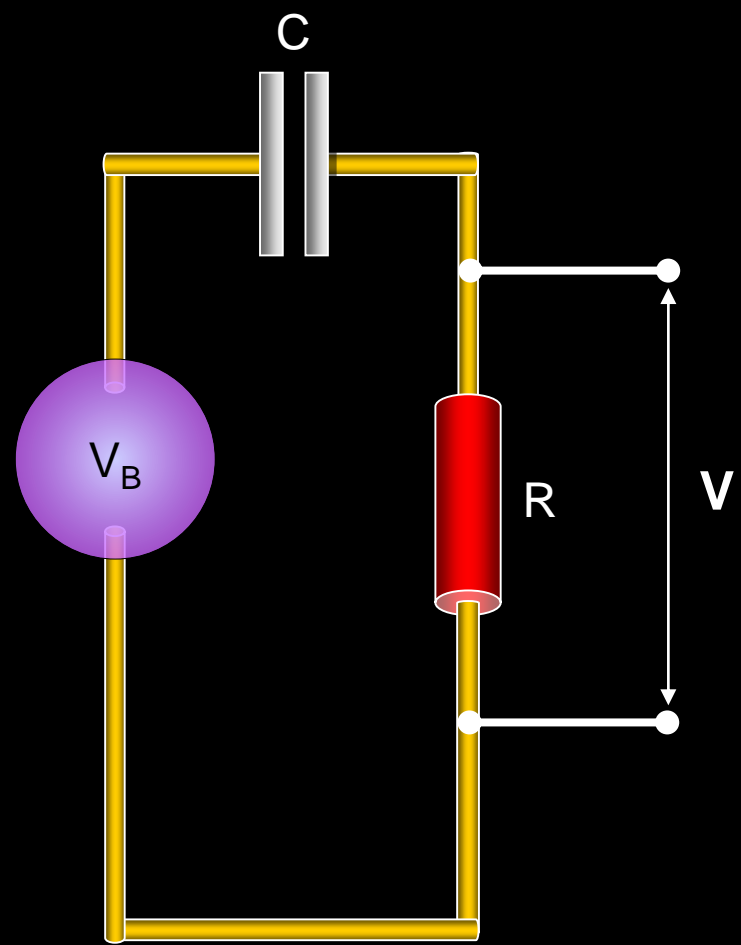




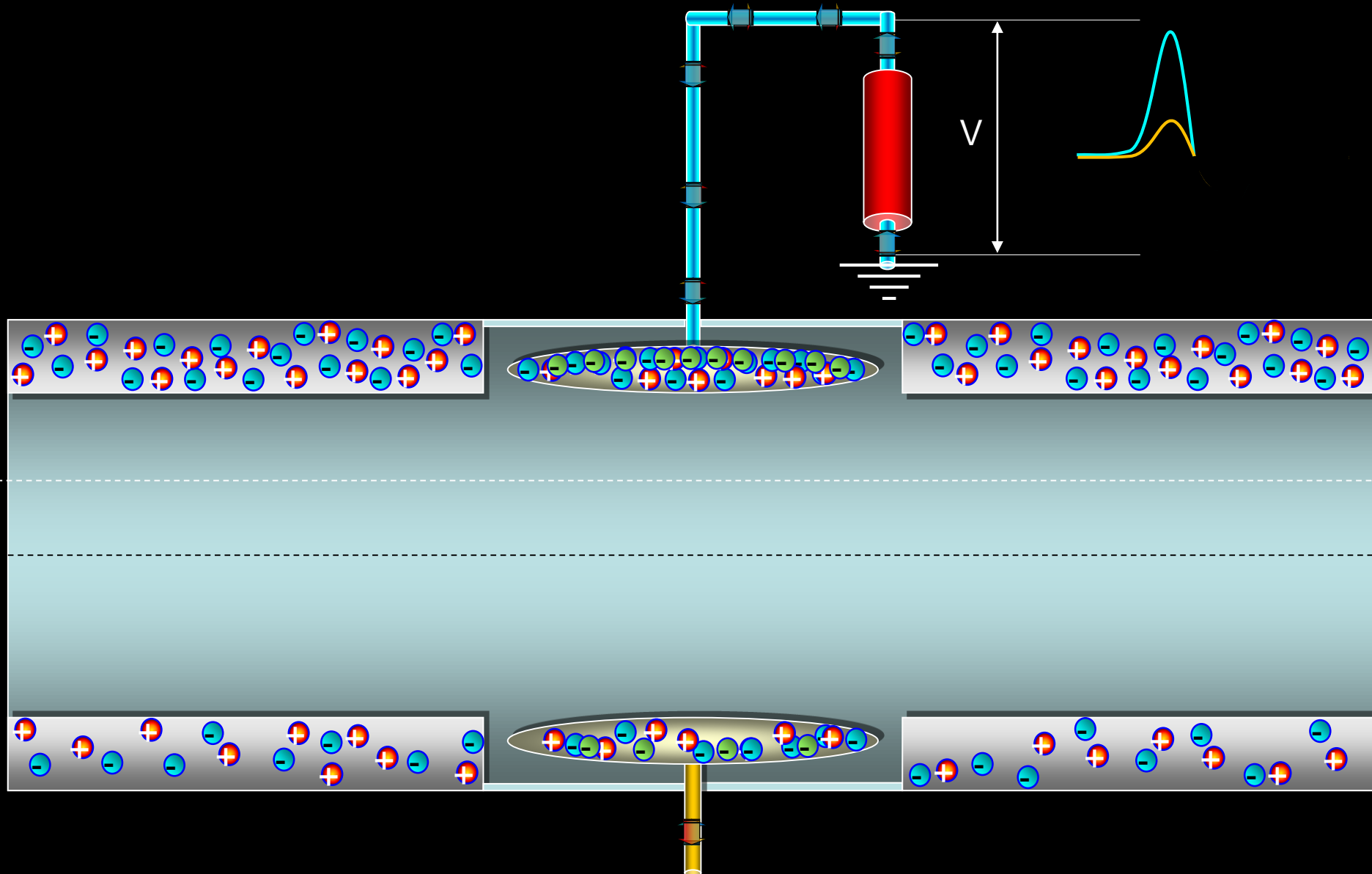
# Electrostatic Monitor – The Principle



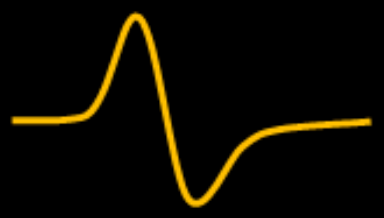
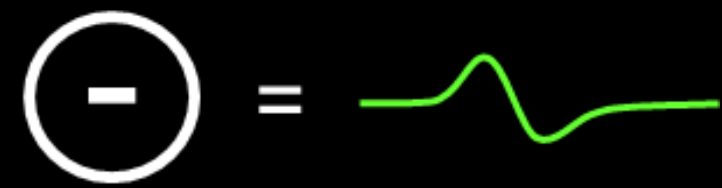
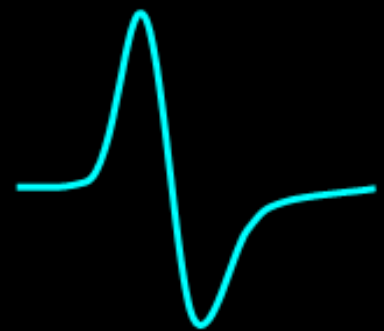
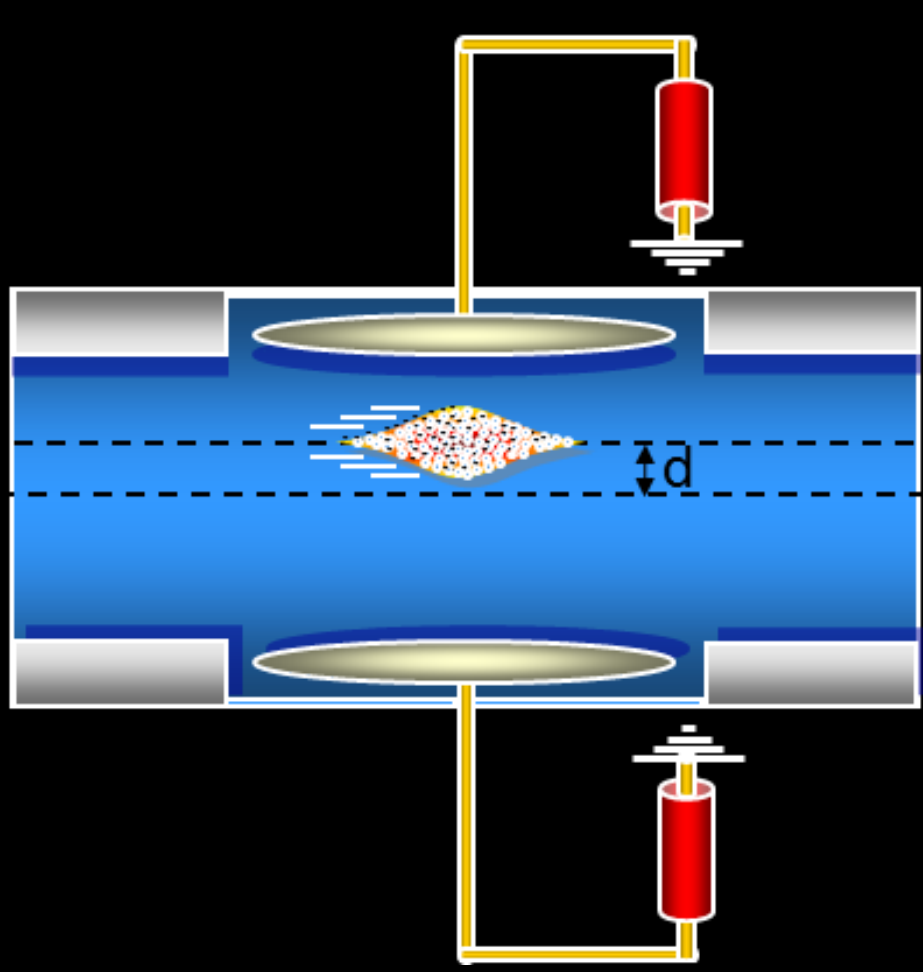
# Electrostatic Monitor – Beam Response



# Electrostatic Beam Position Monitor



# Electrostatic Monitor – The Principle



# Electrostatic Pick-up – Button

- ✓ Low cost  $\Rightarrow$  most popular
- ✗ Non-linear

- requires correction algorithm when beam is off-centre

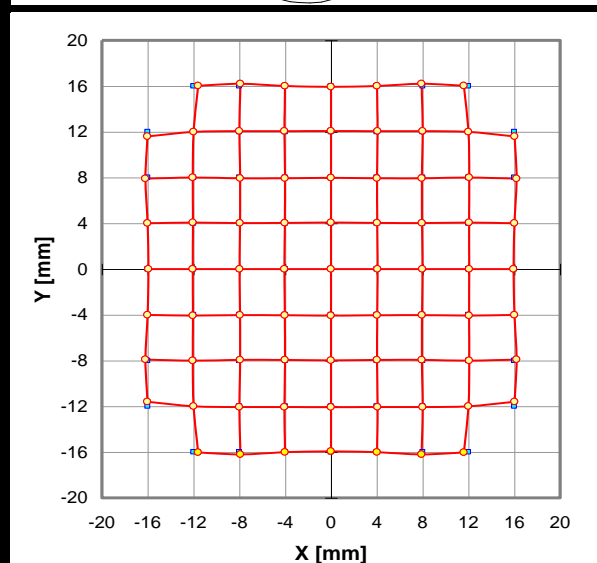
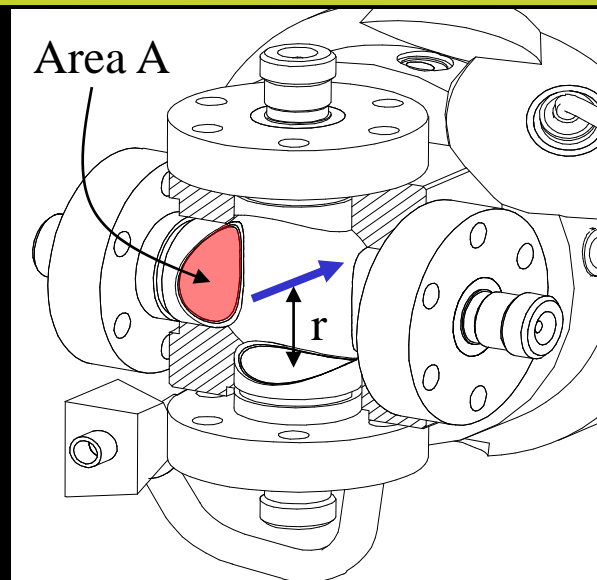
For Button with Capacitance  $C_e$  & Characteristic Impedance  $R_0$

Transfer Impedance:

$$Z_{T(f \gg f_c)} = \frac{A}{(2\pi r) \times c \times C_e}$$

Lower Corner Frequency:

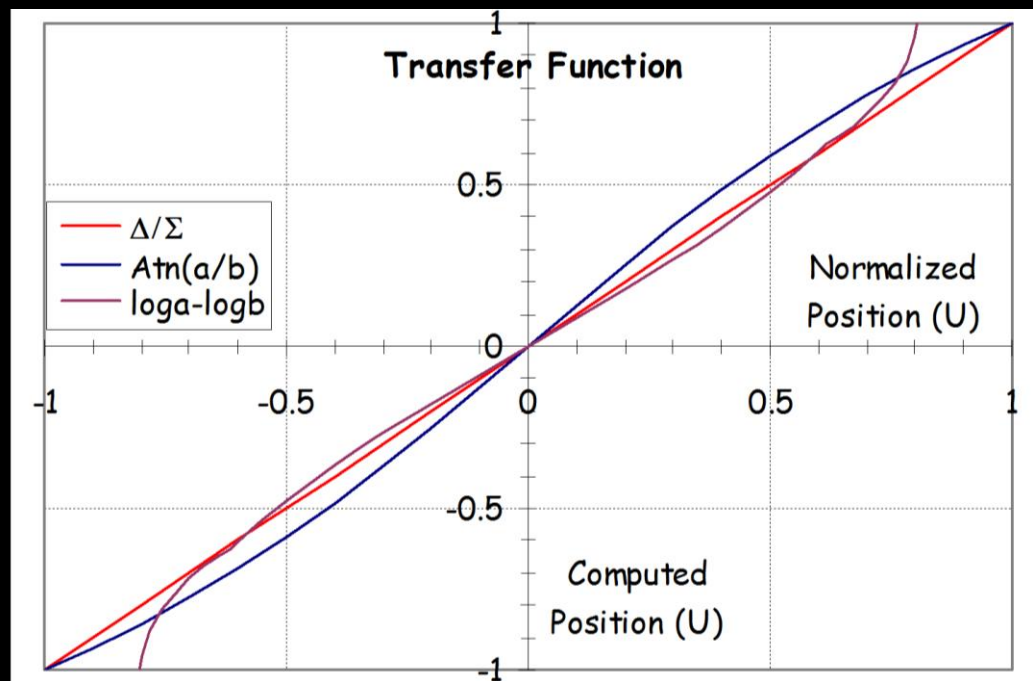
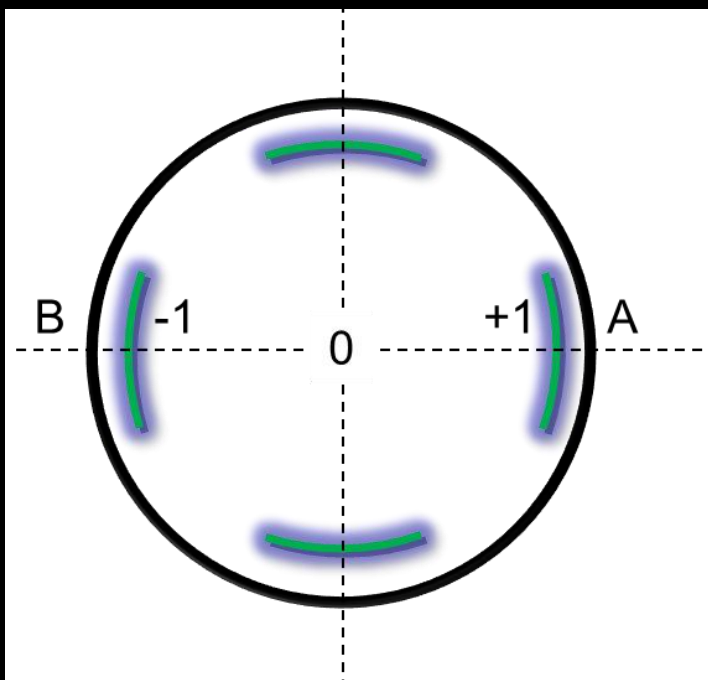
$$f_L = \frac{1}{2\pi R_0 C_e}$$



$$X = 2.30 \cdot 10^{-5} X_1^5 + 3.70 \cdot 10^{-5} X_1^3 + 1.035 X_1 + 7.53 \cdot 10^{-6} X_1^3 Y_1^2 + 1.53 \cdot 10^{-5} X_1 Y_1^4$$

# Normalising the Position Reading

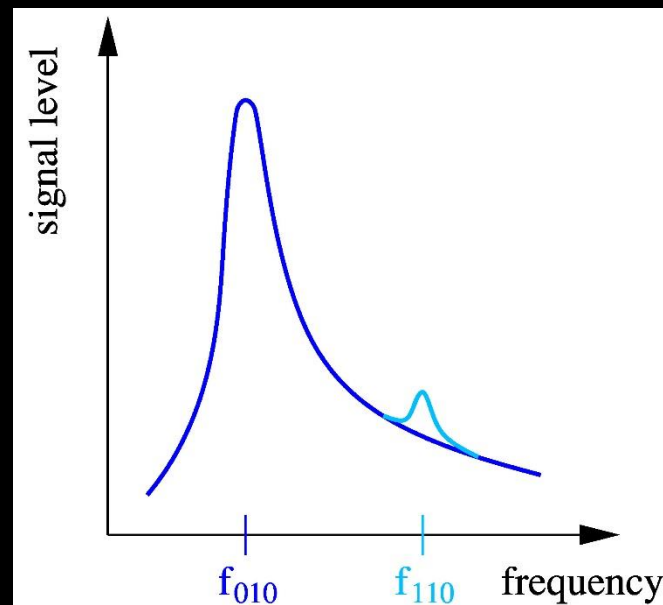
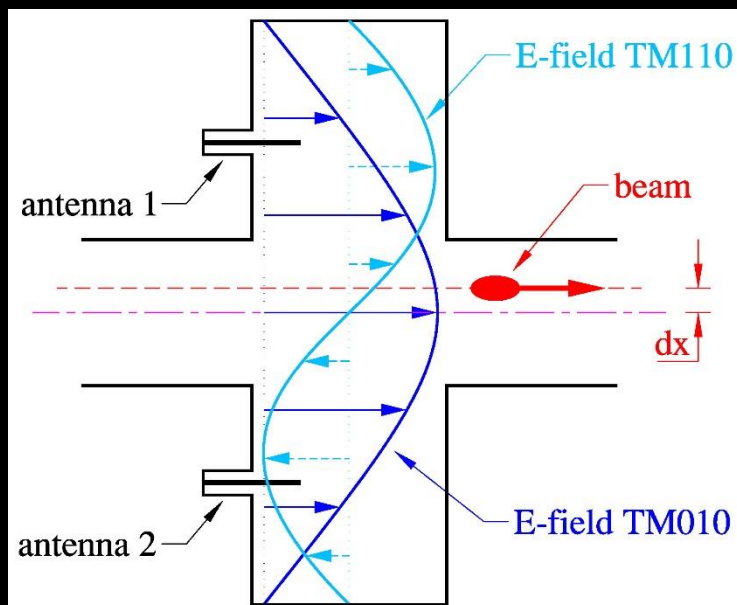
- To make it independent of intensity
- 3 main methods:
  - Difference/Sum :  $(V_A - V_B) / (V_A + V_B) = \Delta / \Sigma$
  - Phase :  $\text{Arctan}(V_A / V_B)$
  - Logarithm :  $\text{Log}(V_A) - \text{Log}(V_B) = \frac{\text{Log}(V_A)}{\text{Log}(V_B)}$





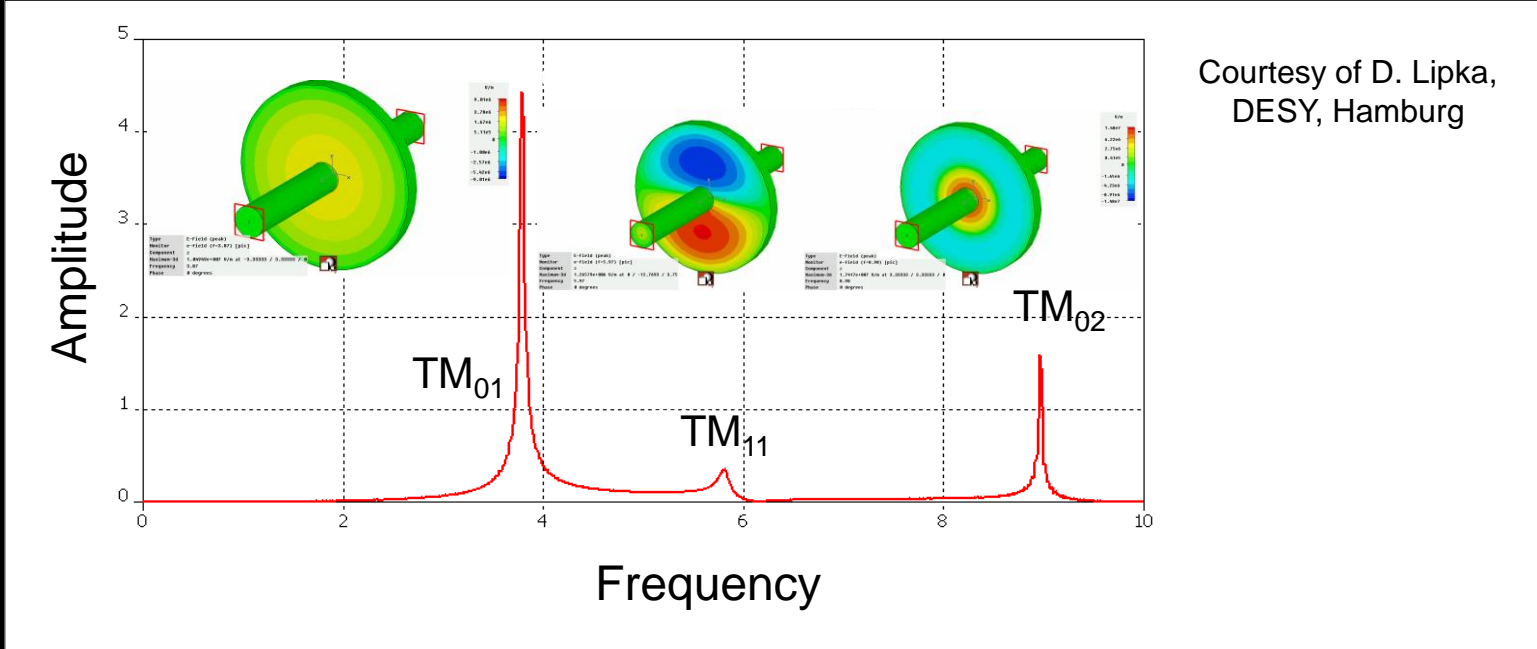
# Improving Precision for Next Generation Accelerators

- BPM electrodes typically give “intensity signals” with some position dependence!
  - Need to remove intensity content to get to the position
  - Difficult to do electronically without some intensity information leaking through
    - When looking for small differences this leakage can dominate the measurement
- **Solution – cavity BPM allowing sub micron resolution**
  - Design the detector to collect only the difference signal
    - Dipole Mode  $TM_{11}$  proportional to POSITION OFFSET (& intensity)
    - Shifted in frequency with respect to intensity dependent Monopole Mode  $TM_{01}$





# Cavity Beam Position Monitors



### Monopole Mode

Type	E-Field (peak)
Monitor	e-Field (F=3.88) [pic]
Component	Normal
Maximum-3d	1.17338e+007 U/m at -3.5 / 3.5 / 0
Frequency	3.88
Phase	0 degrees

Obtain signal using waveguides that only couple to dipole mode for further Monopole Suppression

### Dipole Mode

Type	E-Field (peak)
Monitor	e-Field (F=5.65) [pic]
Component	Normal
Maximum-3d	639869 U/m at 0 / 2 / 0
Frequency	5.65
Phase	0 degrees

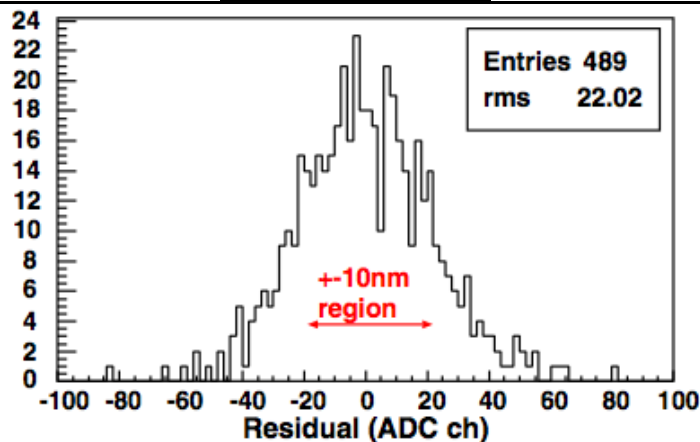
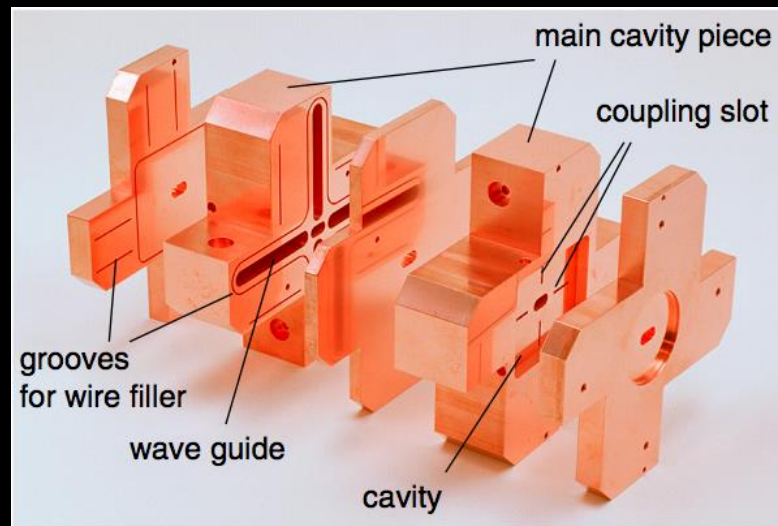
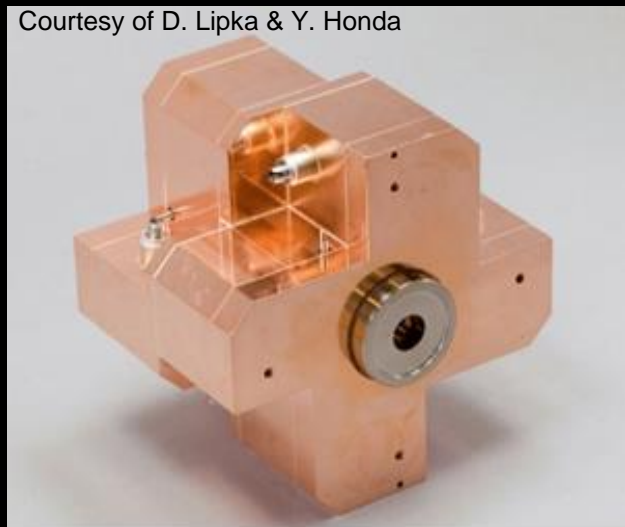


# Today's State of the Art BPMs

- **Prototype BPM for ILC Final Focus**

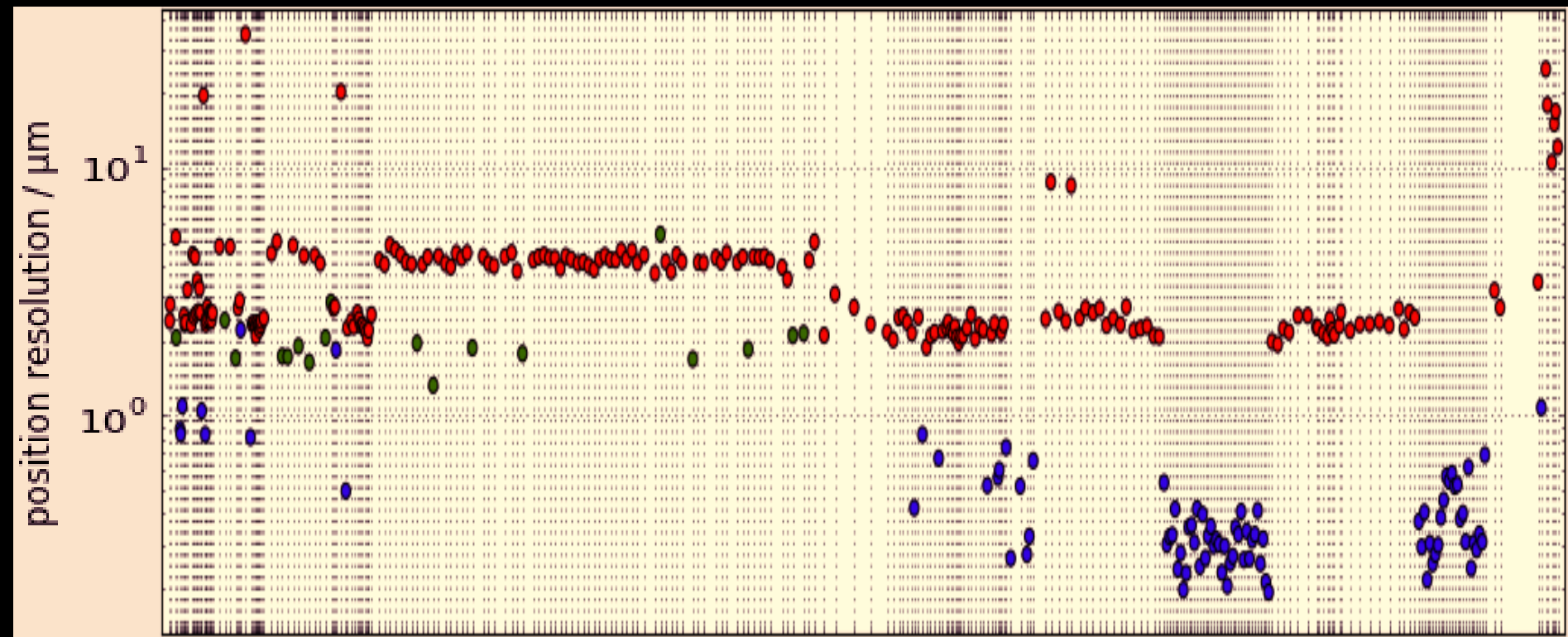
- Required resolution of 2nm (yes nano!) in a  $6 \times 12$ mm diameter beam pipe
- Achieved World Record (so far!) resolution of 8.7nm at ATF2 (KEK, Japan)

Courtesy of D. Lipka & Y. Honda

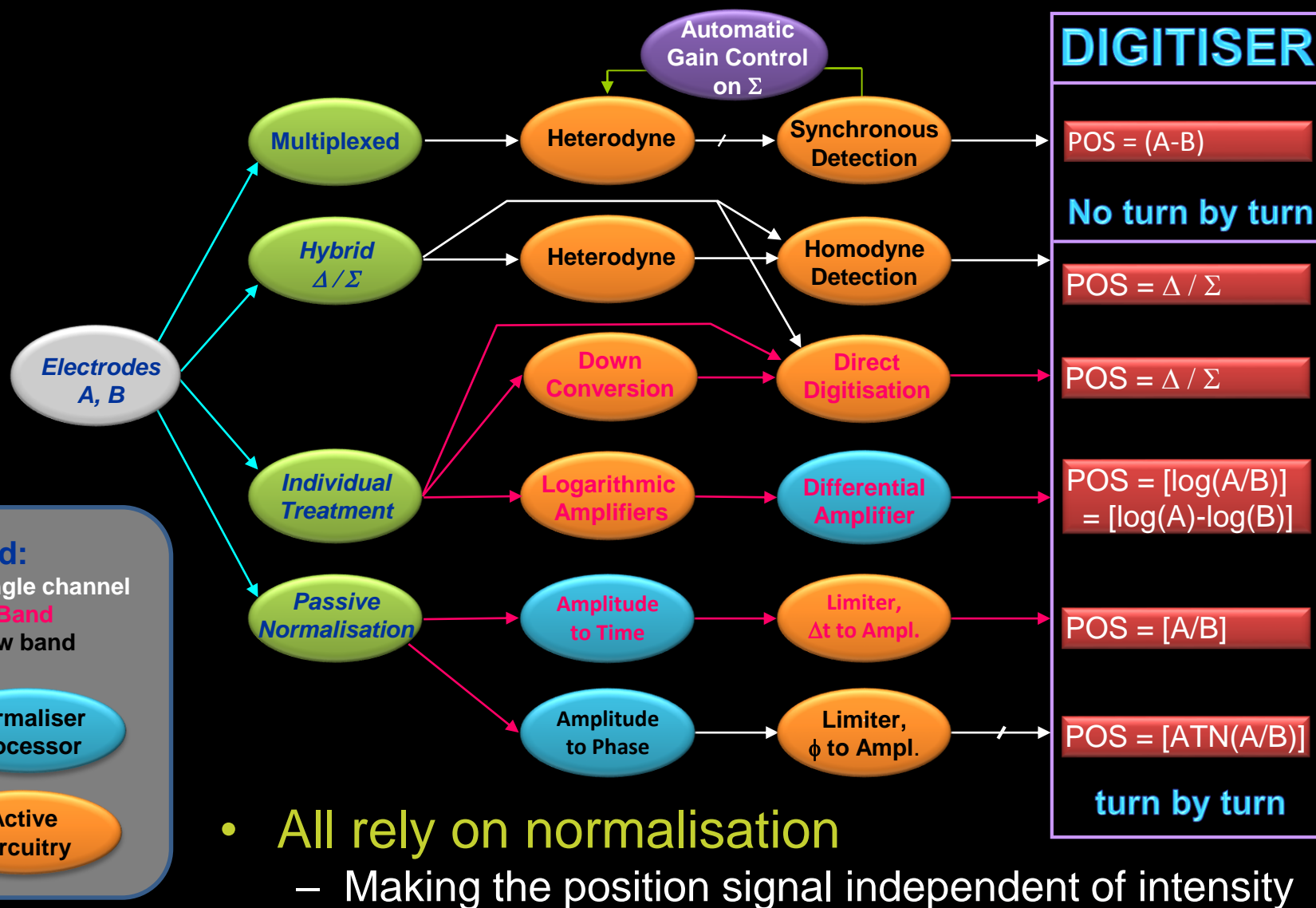


# Comparison of BPM Resolution

- XFEL Data from 2017 Commissioning
  - Standard Button BPMs : 78 mm & 40.5 mm aperture (RED)
  - Re-entrant cavity BPMs : 78 mm aperture (GREEN)
  - Cavity BPMs : 40.5 mm and 10 mm aperture (BLUE)



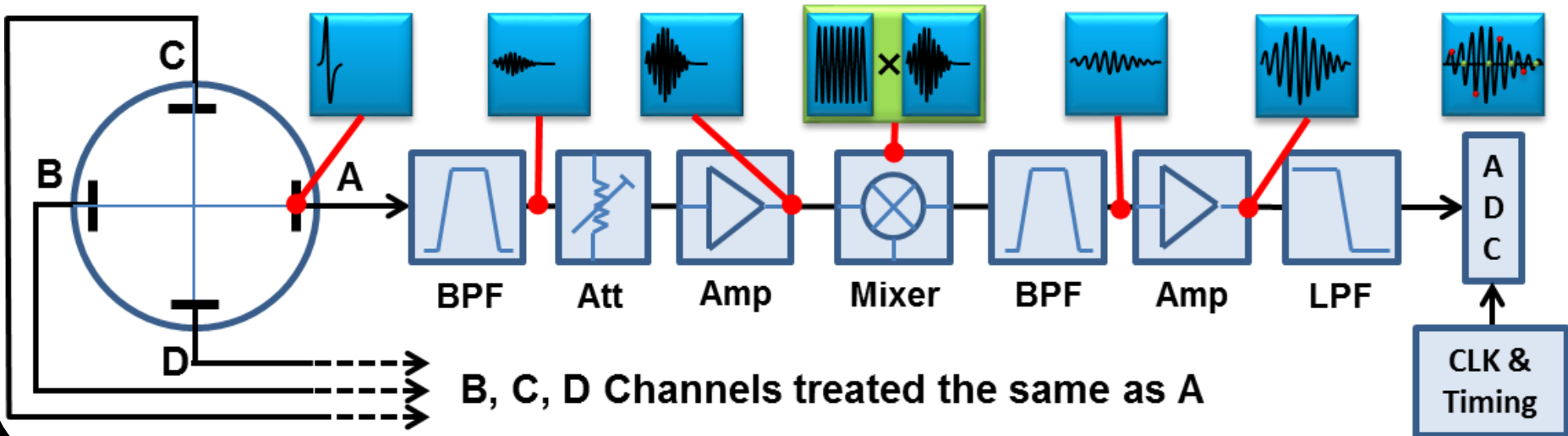
# Processing System Families

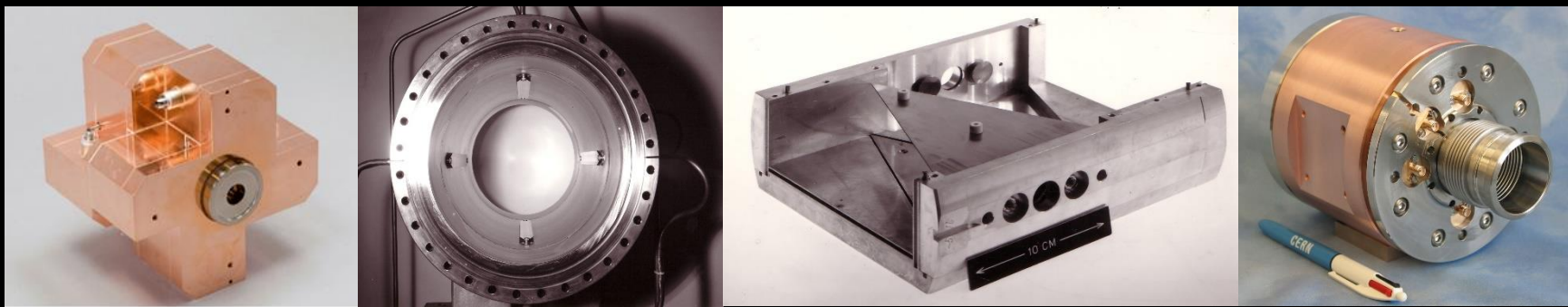


# Modern BPM Read-out Electronics

- Based on the individual treatment of the electrode signals
  - Use of frequency domain signal processing techniques
    - Developed for telecommunications market
  - Rely on high frequency & high resolution analogue to digital converters
    - Minimising analogue circuitry
    - Frequency down-conversion used if necessary to adapt to ADC sampling rate
    - All further processing carried out in the subsequent digital electronics

## A-Electrode Analogue Conditioning





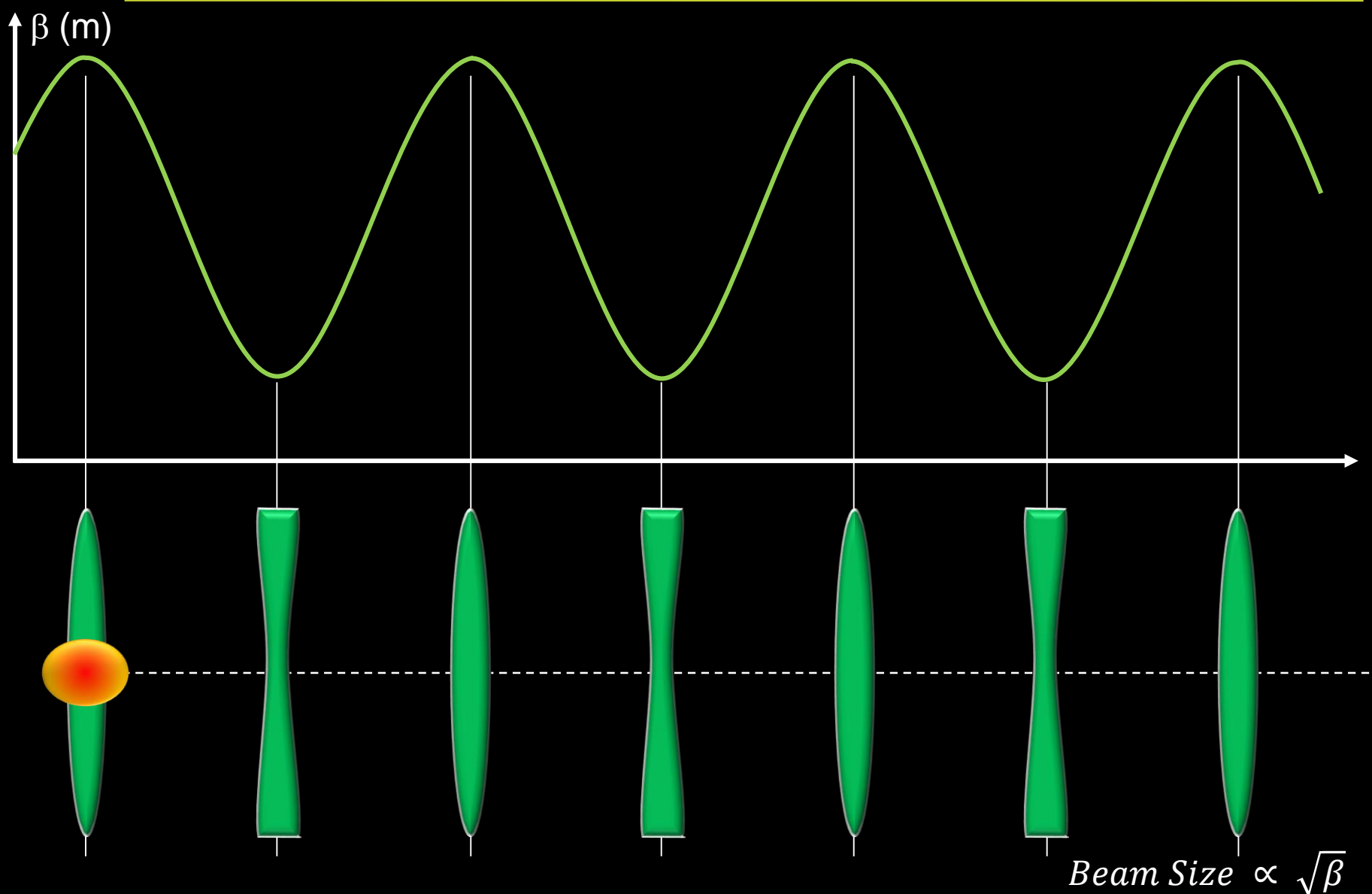
# Diagnostics using Beam Position Systems



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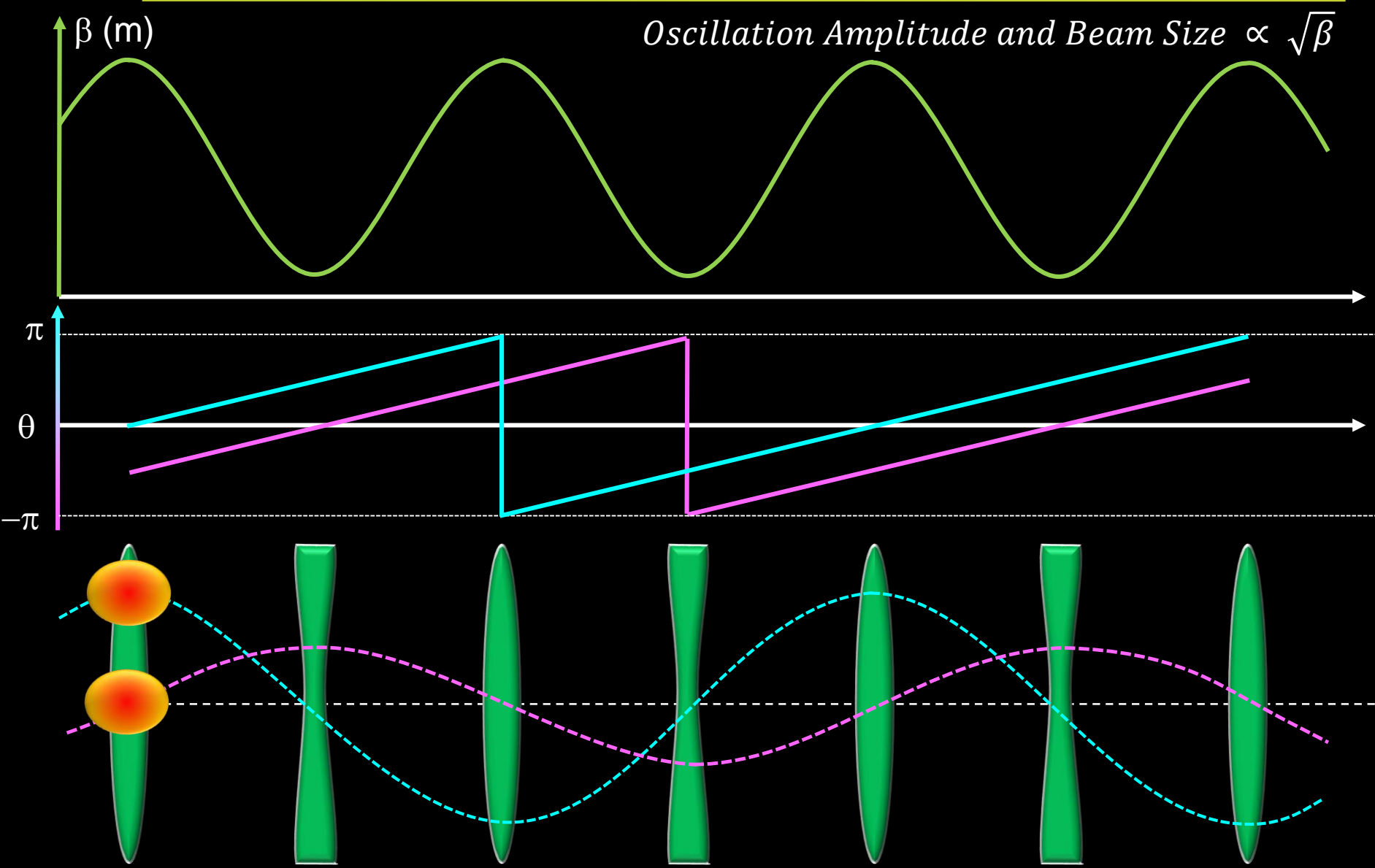


# The Machine $\beta$ -Function





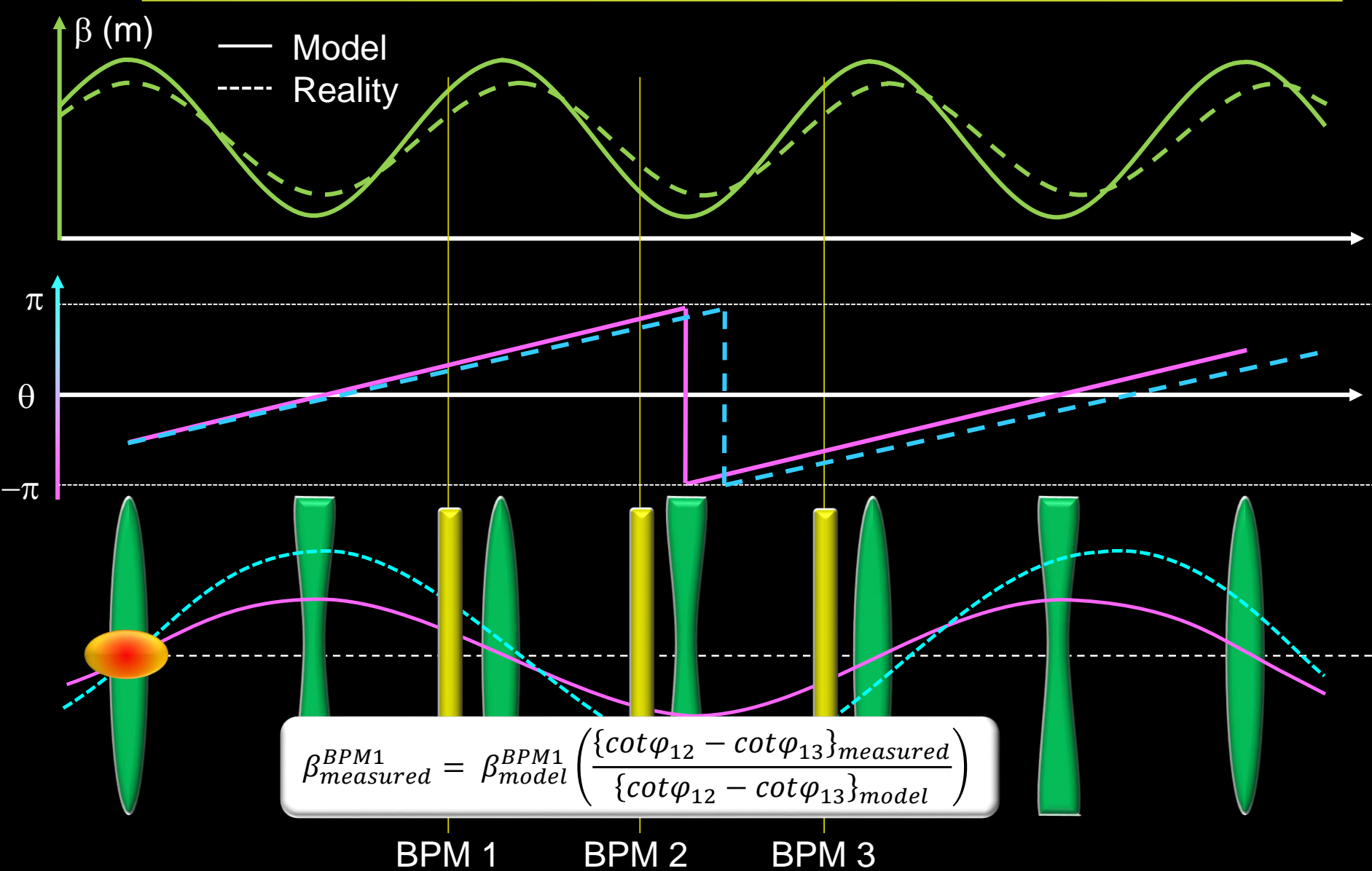
# The Machine $\beta$ -Function







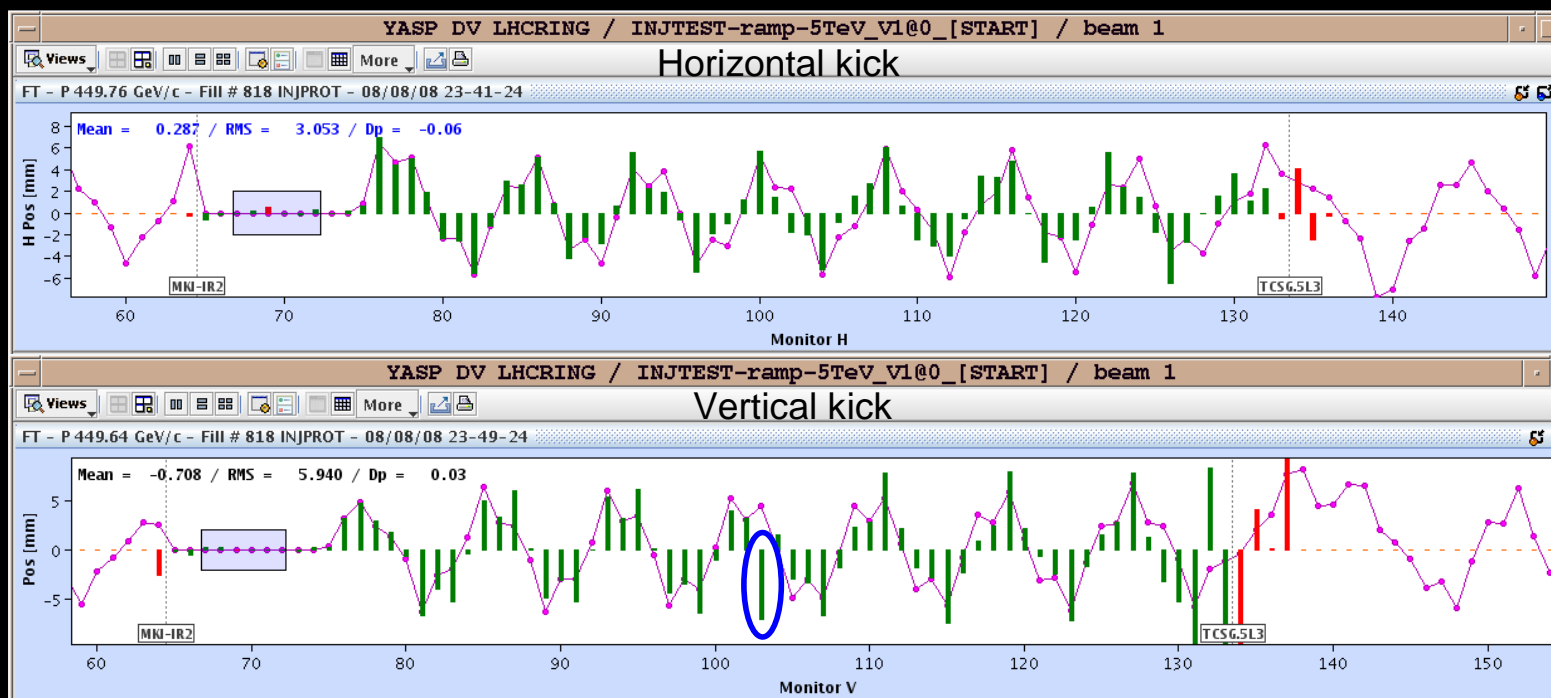
# The Machine $\beta$ -Function



# Analysis of BPM Data

- On line analysis of BPM Data

- Polarity errors easily identified with 45° BPM sampling
- Quick indication of phase advance errors
- Used to verify optics functions
  - e.g. matching from transfer lines into ring



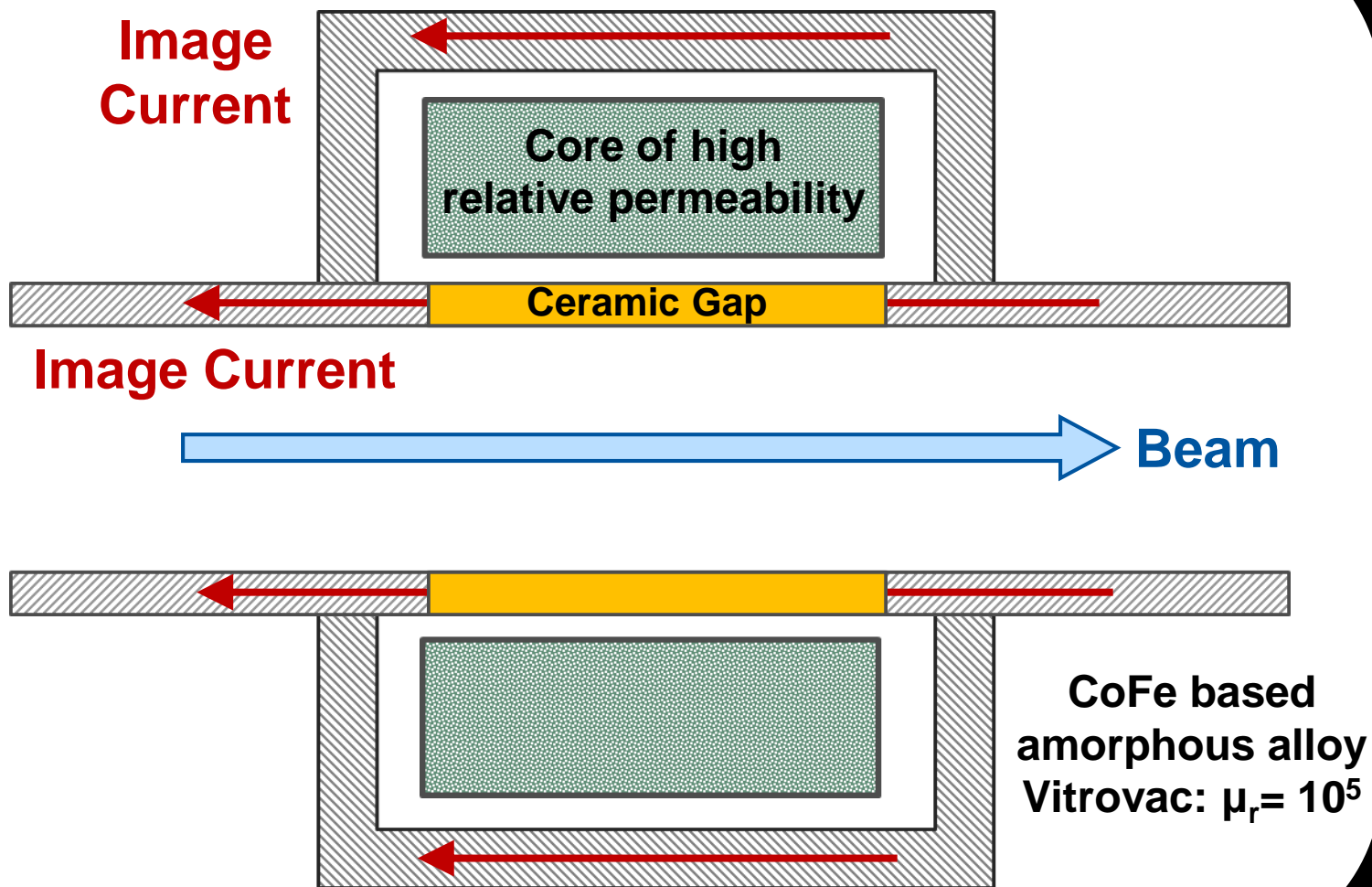
Optics phase error

BPM polarity error

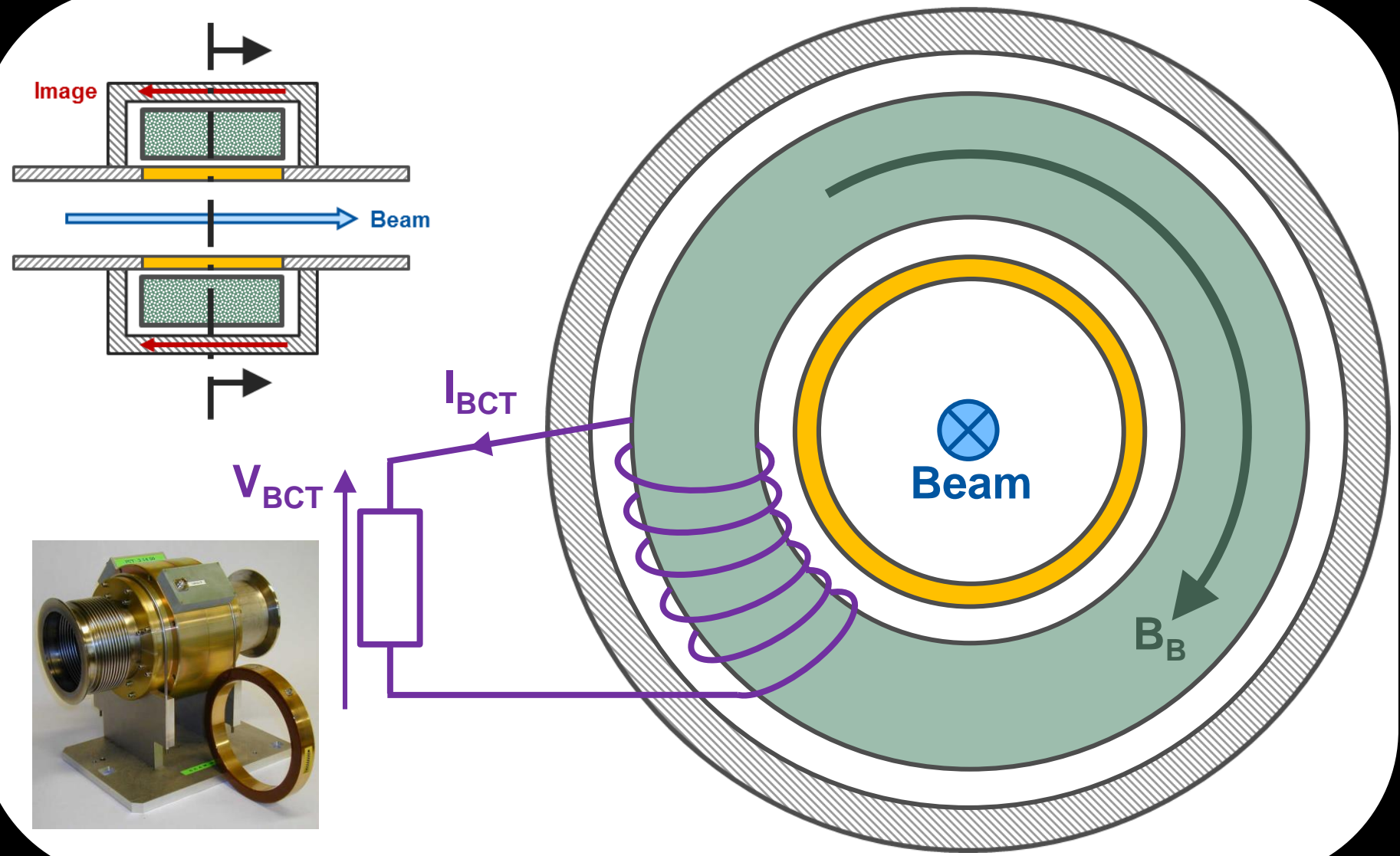


# Beam Intensity Monitors

# AC (Fast) Current Transformers



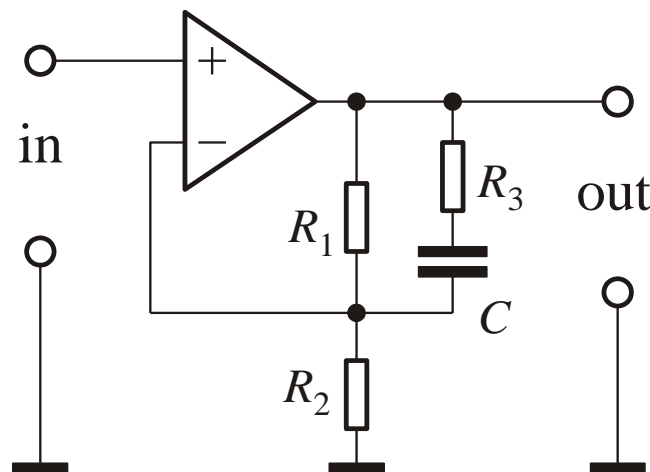
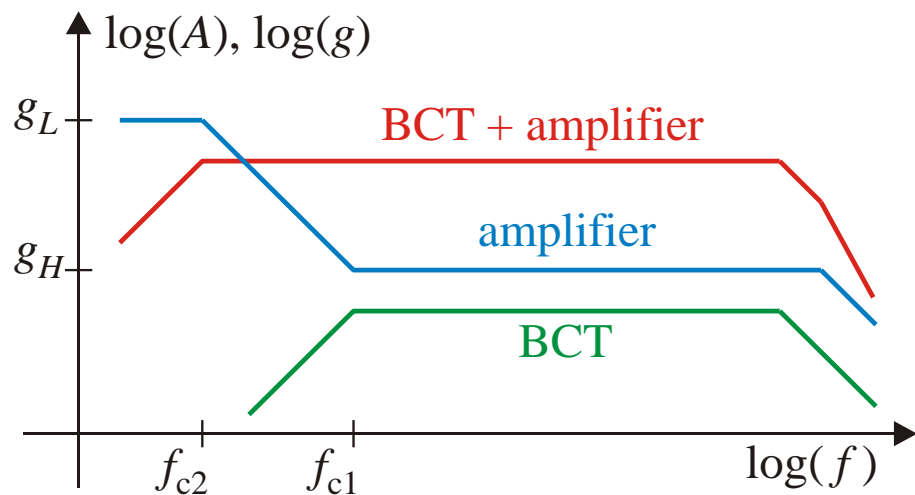
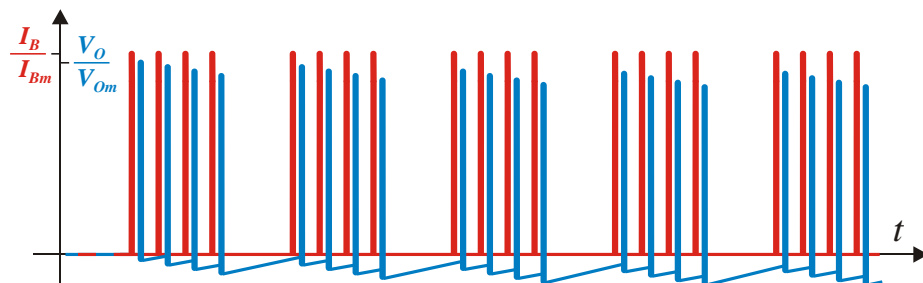
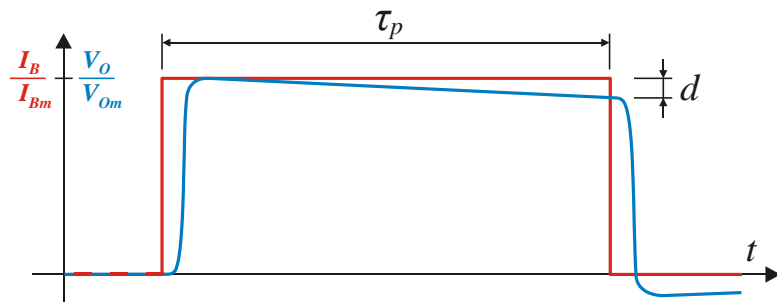
# AC (Fast) Current Transformers



# AC (Fast) Transformer Response

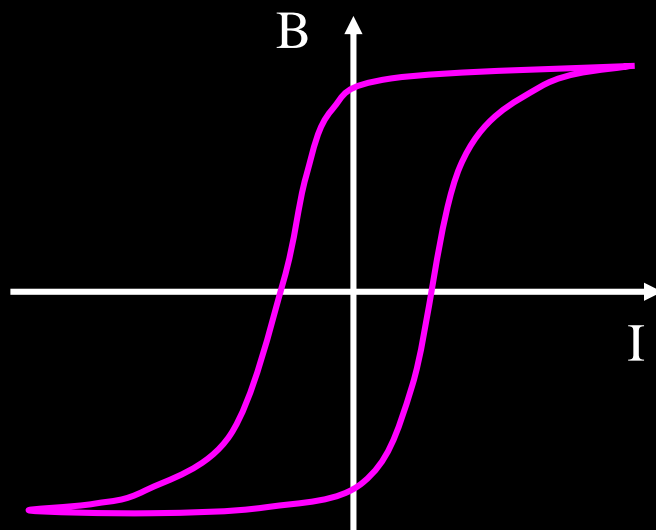
- **Low cut-off**

- Impedance of secondary winding decreases at low frequency
- Results in signal droop and baseline shift
- Mitigated by baseline restoration techniques (analogue or digital)



# The DC transformer

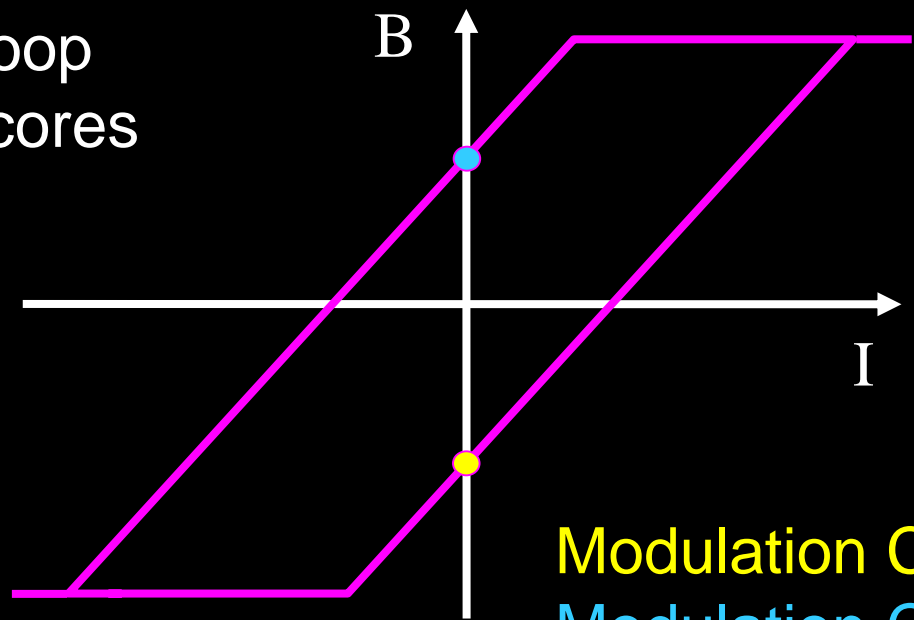
- AC transformers can be extended to very low frequency but not to DC ( no  $dl/dt$  ! )
- DC measurement is required in storage rings
- To do this:
  - Take advantage of non-linear magnetisation curve
  - Use 2 identical cores modulated with opposite polarities



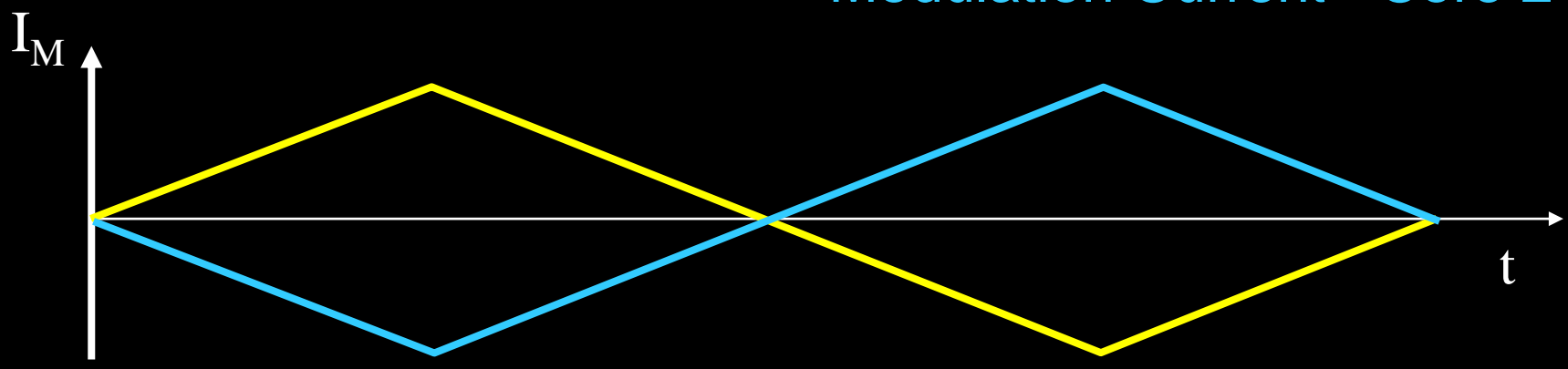


# DCCT Principle – Case 1: no beam

Hysteresis loop of modulator cores



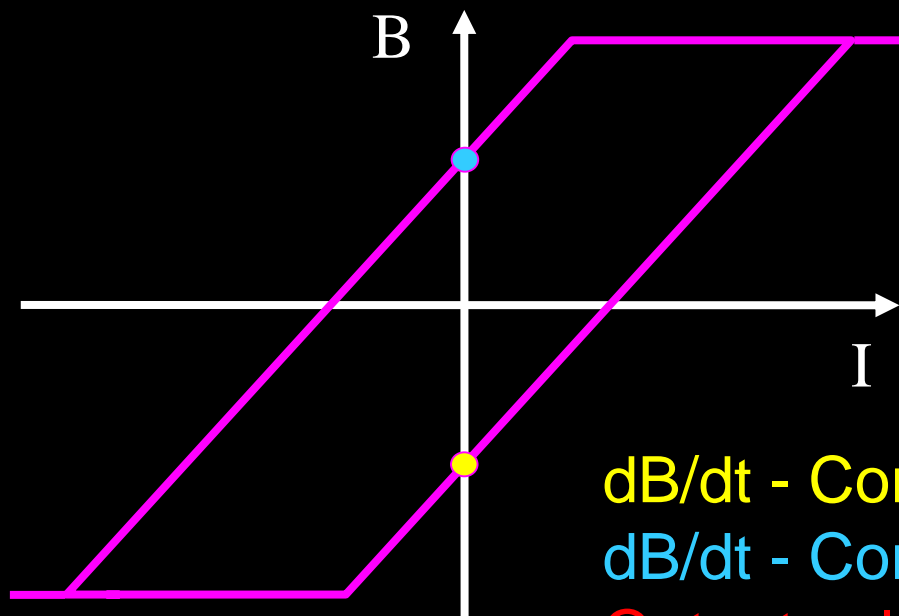
Modulation Current - Core 1  
Modulation Current - Core 2





# DCCT Principle – Case 1: no beam

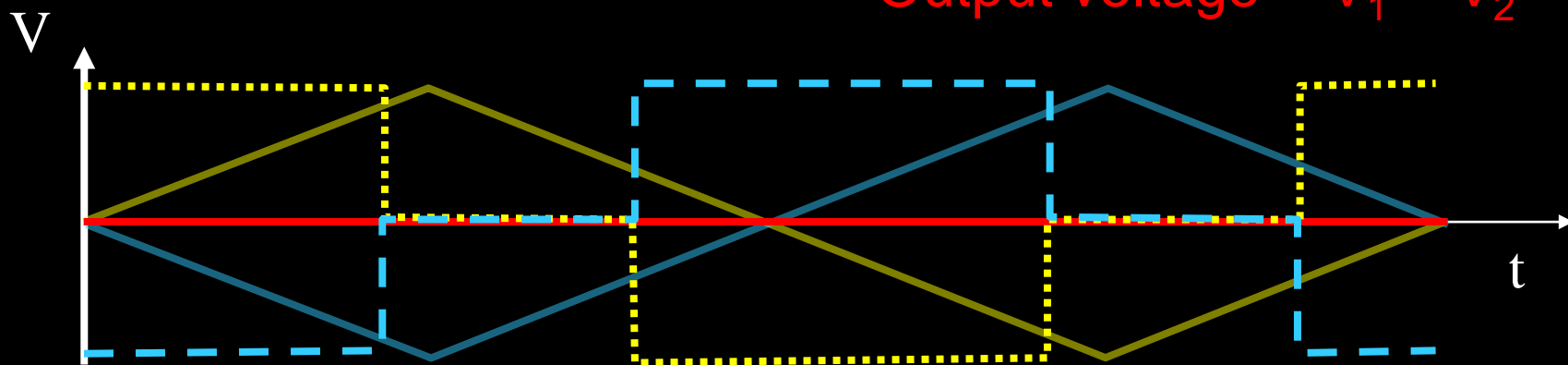
$$V \propto \frac{dB}{dt}$$



$dB/dt$  - Core 1 ( $V_1$ )

$dB/dt$  - Core 2 ( $V_2$ )

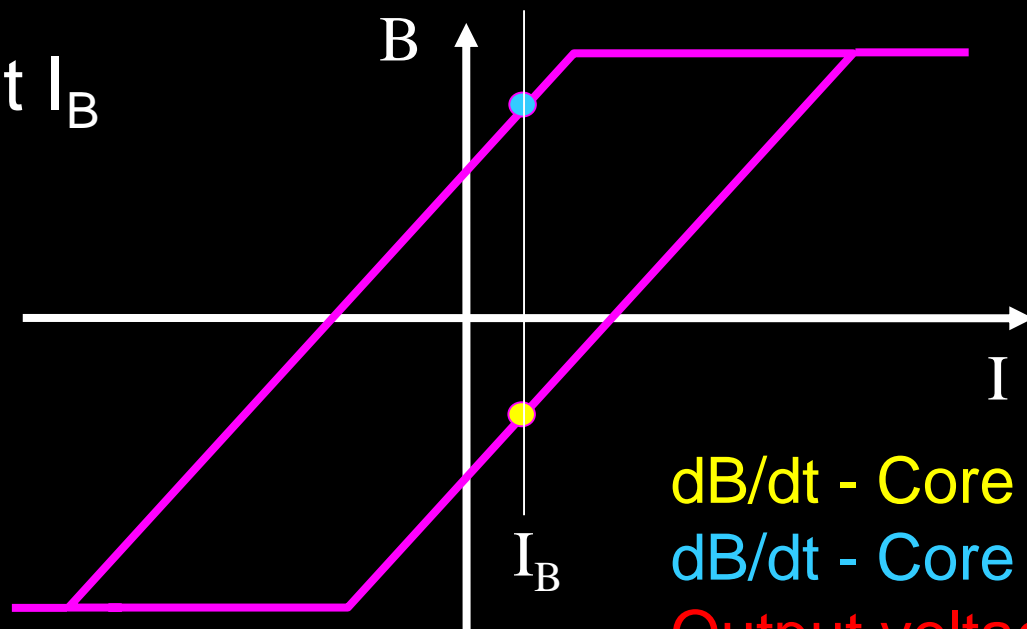
Output voltage =  $V_1 - V_2$



# DCCT Principle – Case 2: with beam

Beam Current  $I_B$

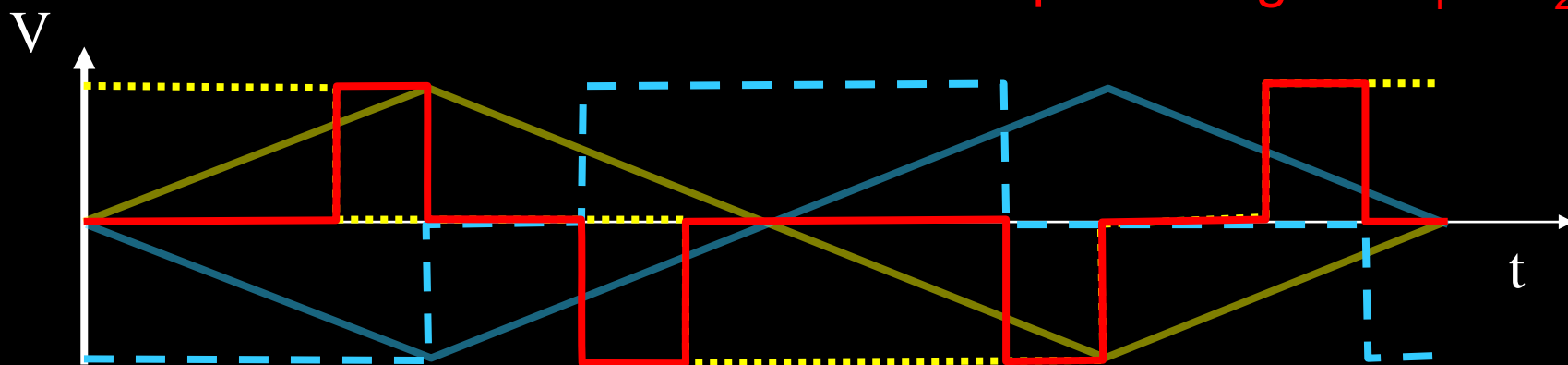
Output signal is at  
TWICE  
the modulation  
frequency



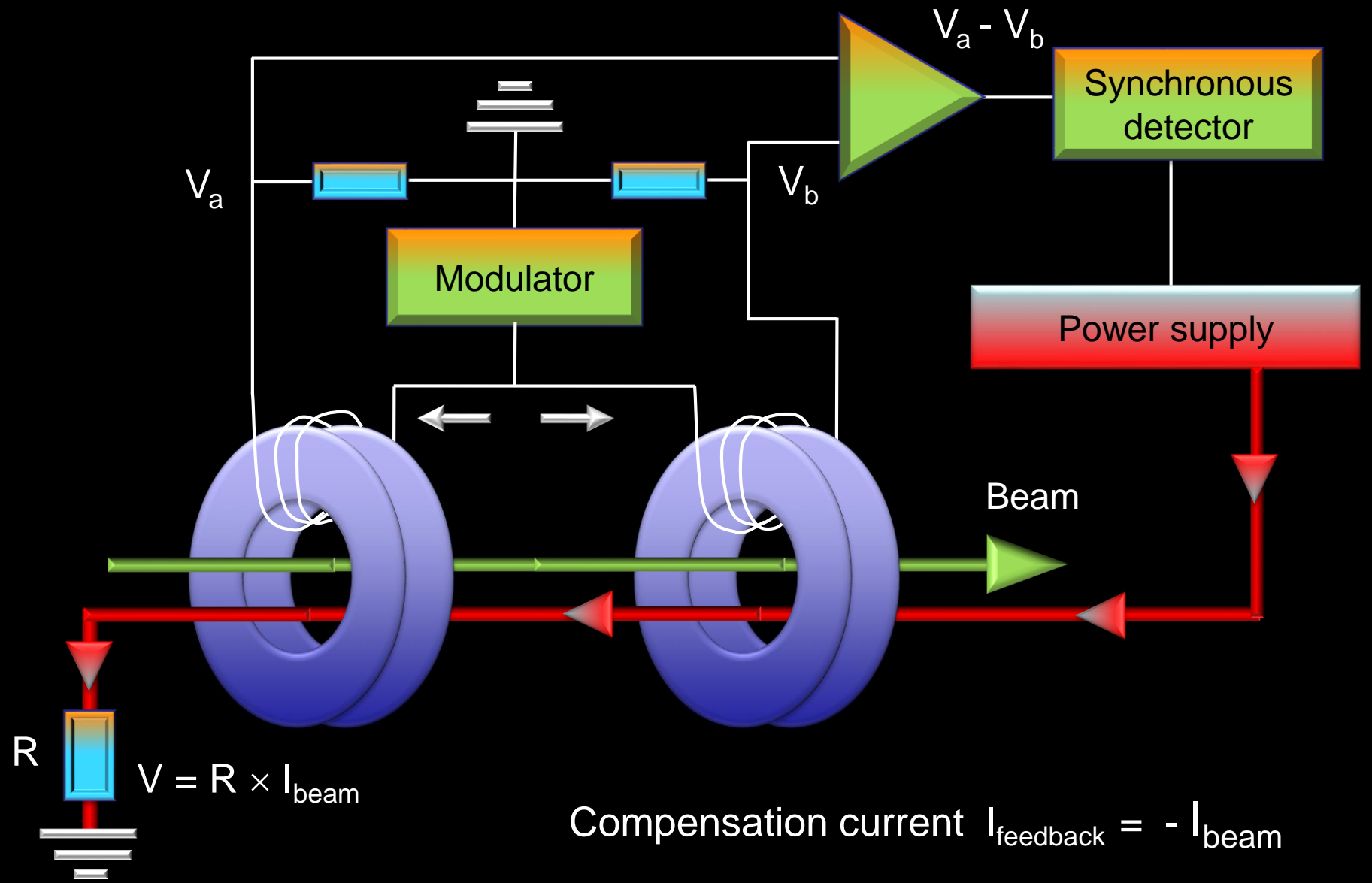
$\frac{dB}{dt}$  - Core 1 ( $V_1$ )

$\frac{dB}{dt}$  - Core 2 ( $V_2$ )

Output voltage =  $V_1 - V_2$



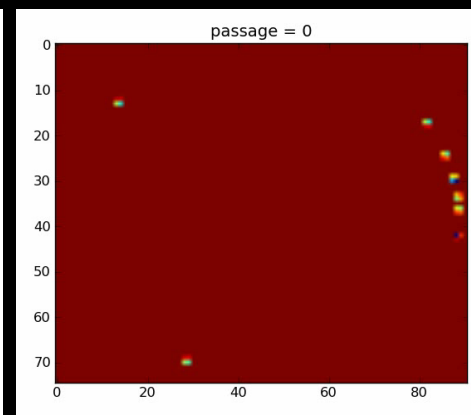
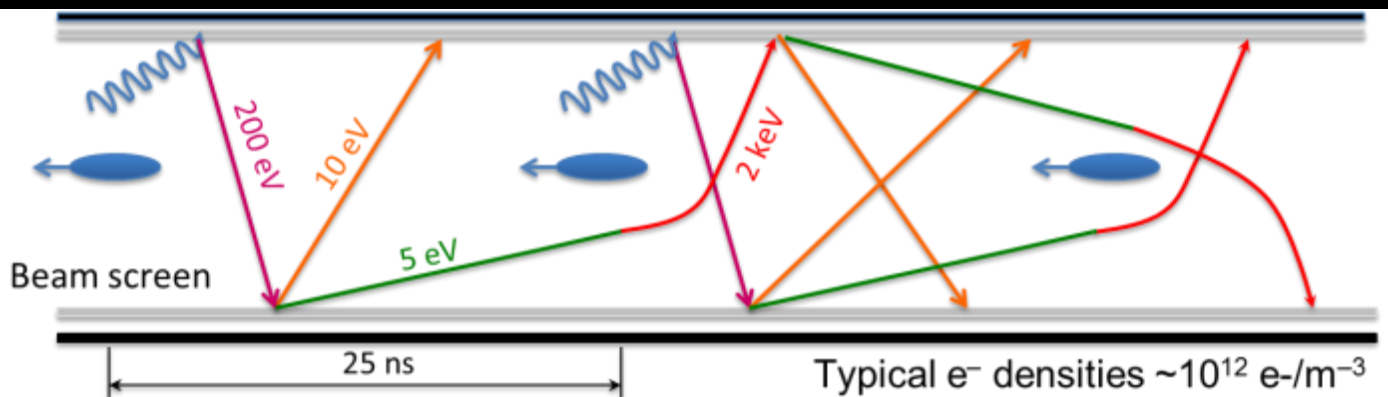
# Zero Flux DCCT Schematic





# Diagnostics using Beam Intensity Monitors

# Monitoring Electron Cloud Activity



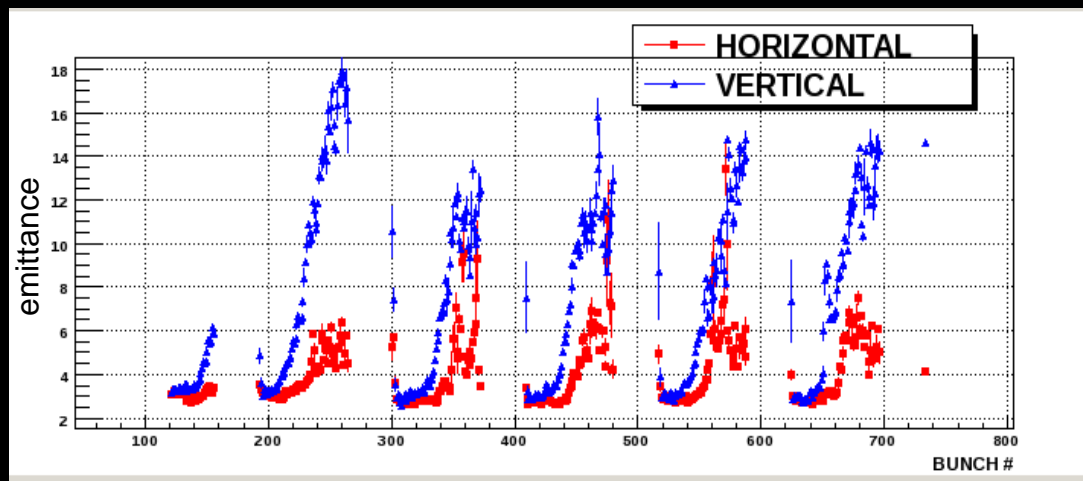
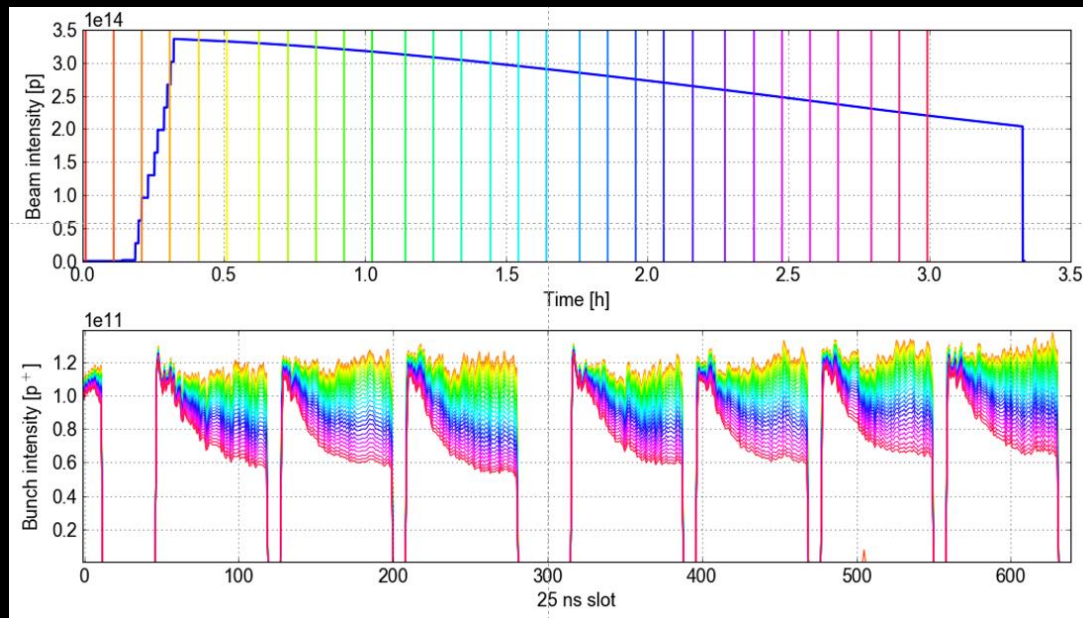
G. Iadarola, G. Rumolo, G. Arduini (CERN)

- **Secondary Emission Yield [SEY]**
  - SEY > Threshold  $\Rightarrow$  avalanche effect (multipacting)
- **Possible consequences:**
  - Instabilities, emittance growth, vacuum degradation, background
  - Energy deposition in cryogenic surfaces
- **Electron bombardment can reduce SEY of a material**
  - A function of the delivered electron dose
  - This technique of “scrubbing” can suppress electron cloud build-up

# Bunch by Bunch Diagnostics

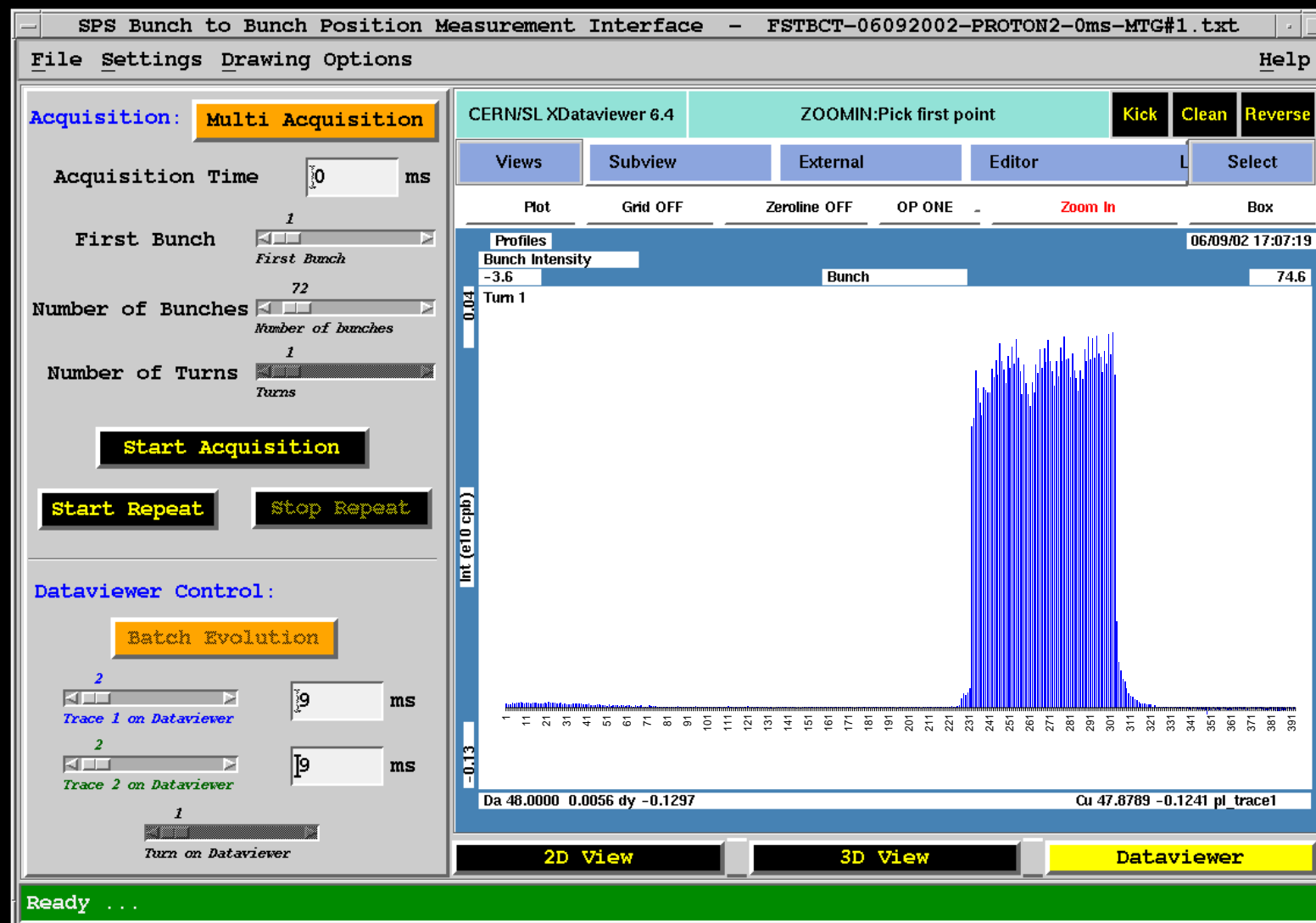
## Electron Cloud in LHC

- Electron cloud creates instability in tail of bunch trains
- Increases the size of the bunches towards the end of each bunch train
- Leads to losses for these bunches
- Adjustments made to counter this effect
  - Chromaticity
  - Transverse feedback
  - Beam scrubbing
- **Diagnostics**
  - LHC fast BCT
    - Allows bunch by bunch intensity measurement
  - LHC Synchrotron Light Monitor
    - Gated intensified Camera
    - Allows bunch by bunch profile measurement





# Diagnostics using Fact BCTs



Bad RF Capture of a single LHC Batch in the SPS (72 bunches)



# Beam Loss Monitors

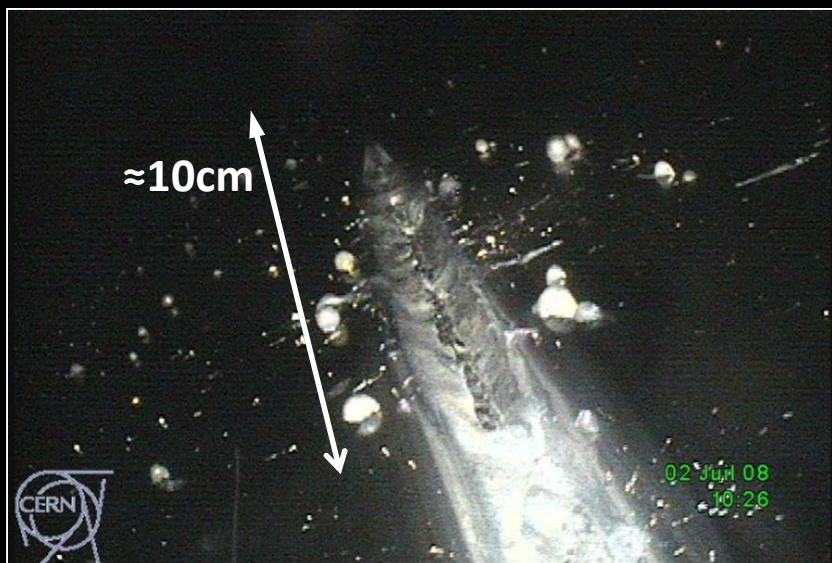


# Beam Loss Detectors

- **Role of a BLM system:**
  - Protect the machine from damage
  - Dump the beam to avoid magnet quenches (for superconducting magnets)
  - Diagnostic tool to improve the performance of the accelerator
- **E.g. LHC**

Stored Energy	
Beam 7 TeV	2 x 362 MJ

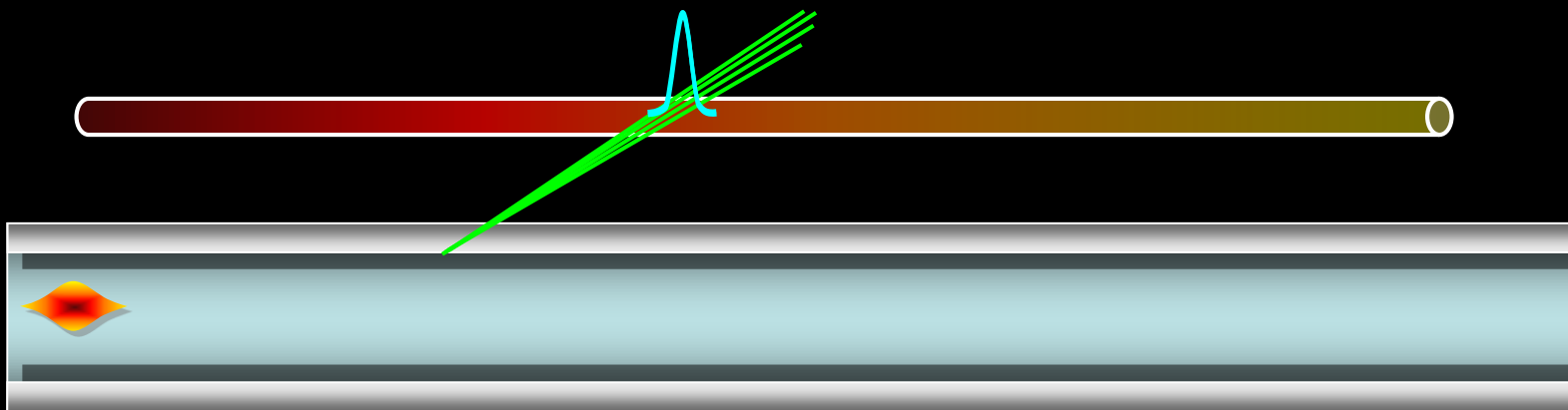
Quench and Damage at 7 TeV	
Quench level	$\approx 1 \text{ mJ/cm}^3$
Damage level	$\approx 1 \text{ J/cm}^3$



- **SPS incident**
  - June 2008
  - 2 MJ beam lost at 400 GeV

# Beam Loss Detectors

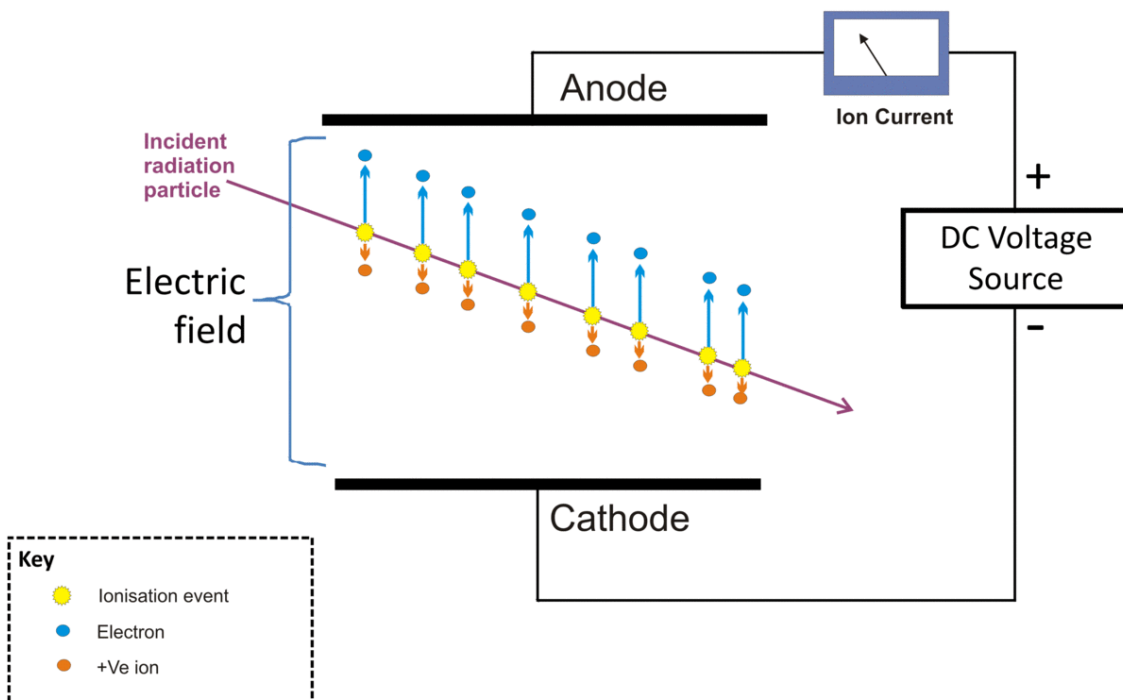
- Common types of monitor
  - Long ionisation chamber (charge detection)
    - Up to several km of gas filled hollow coaxial cables
    - Position sensitivity achieved by comparing direct & reflected pulse
      - e.g. SLAC – 8m position resolution (30ns) over 3.5km cable length
    - Dynamic range of up to  $10^4$
  - Fibre optic monitors
    - Electrical signals replaced by light produced through Cerenkov effect



# Beam Loss Detectors

- Common types of monitor
  - Ionisation chambers
  - Dynamic range of  $< 10^8$
  - Slow response ( $\mu\text{s}$ ) due to ion drift time

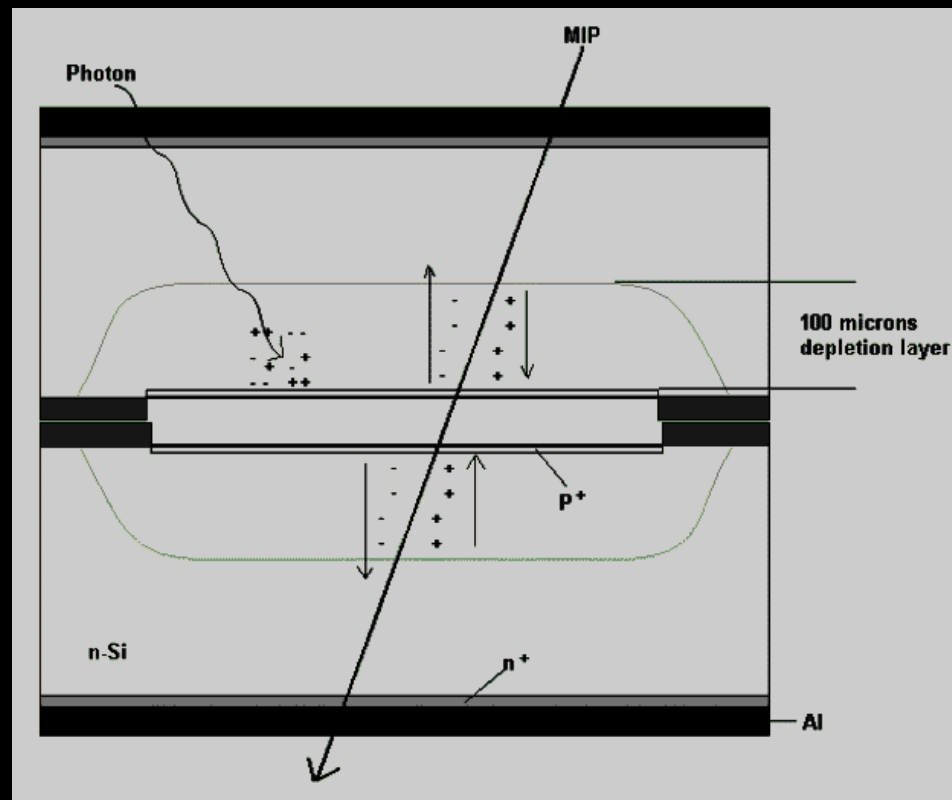
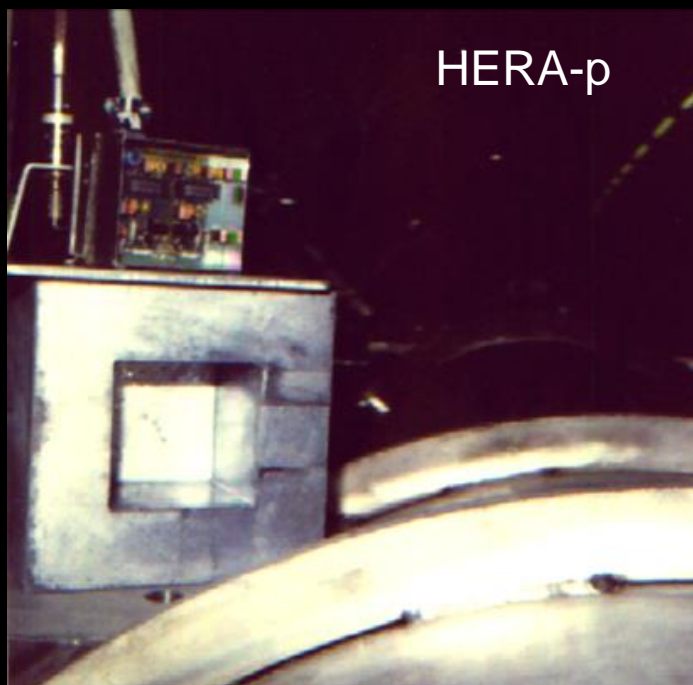
## Visualisation of ion chamber operation



# Beam Loss Detectors

- Common types of monitor

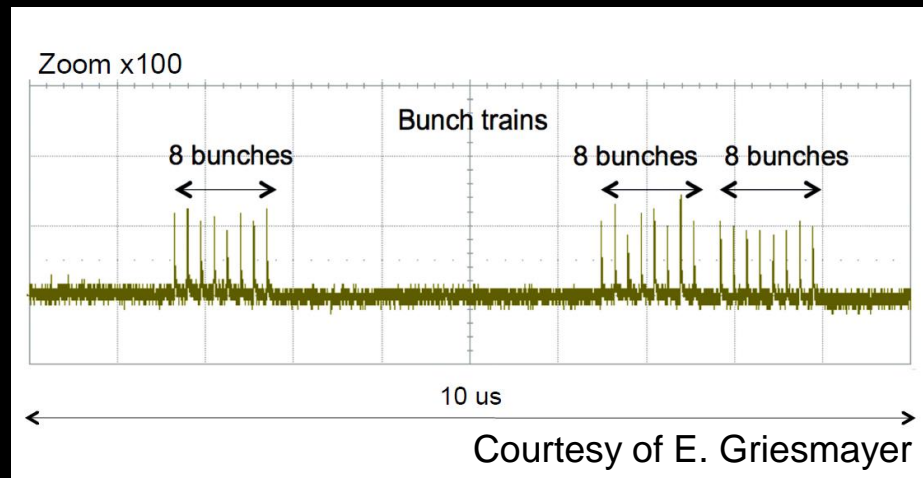
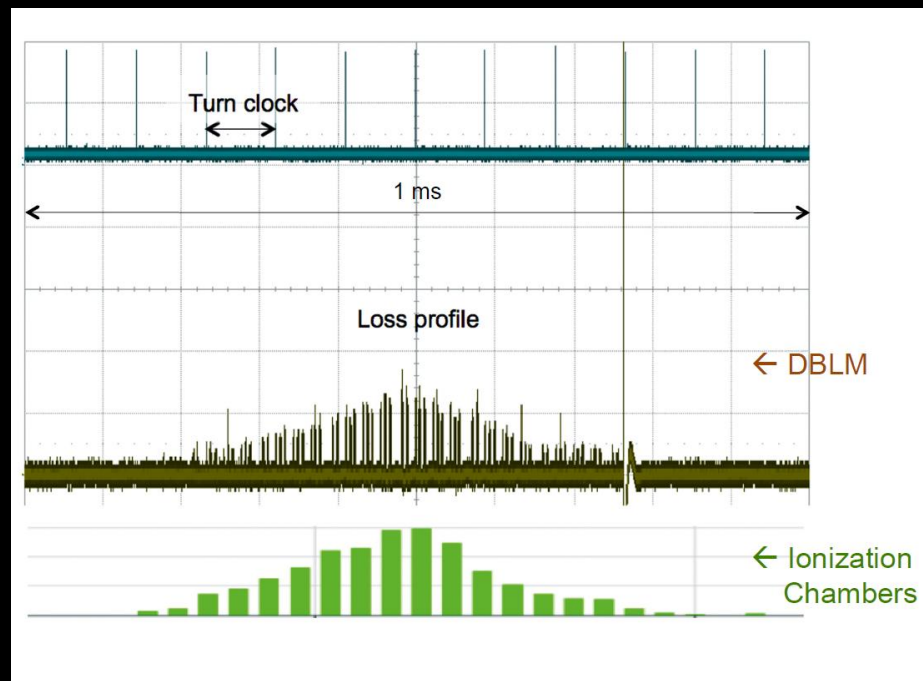
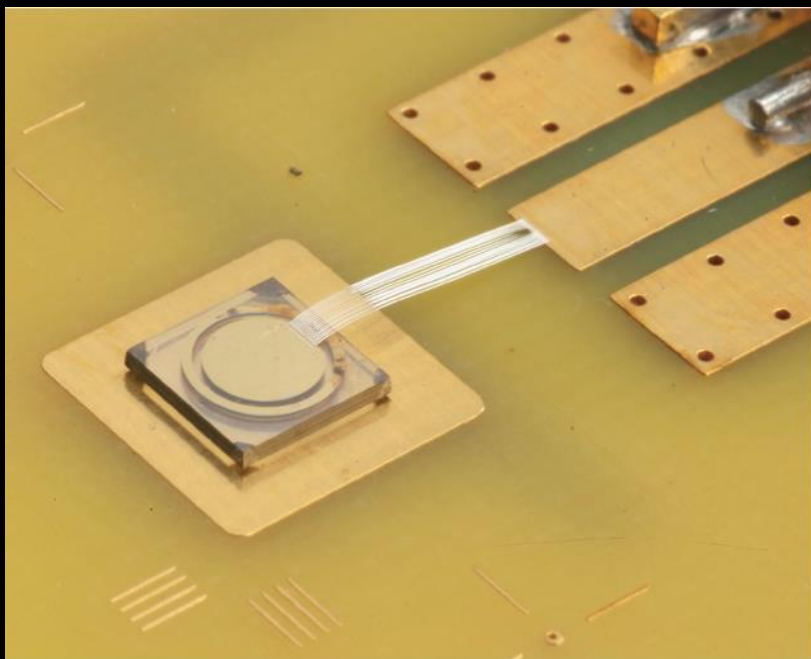
- PIN photodiode (solid state ionisation chamber)
  - Detect coincidence of ionising particle crossing photodiodes
  - Count rate proportional to beam loss with speed limited by integration time
  - Can distinguish between X-rays & ionising particles
  - Dynamic range of up to  $10^9$



# Beam Loss Detectors – New Materials

- **Diamond Detectors**

- Fast & sensitive
- Used in LHC to distinguish bunch by bunch losses
- Investigations now ongoing to see if they can work in cryogenic conditions





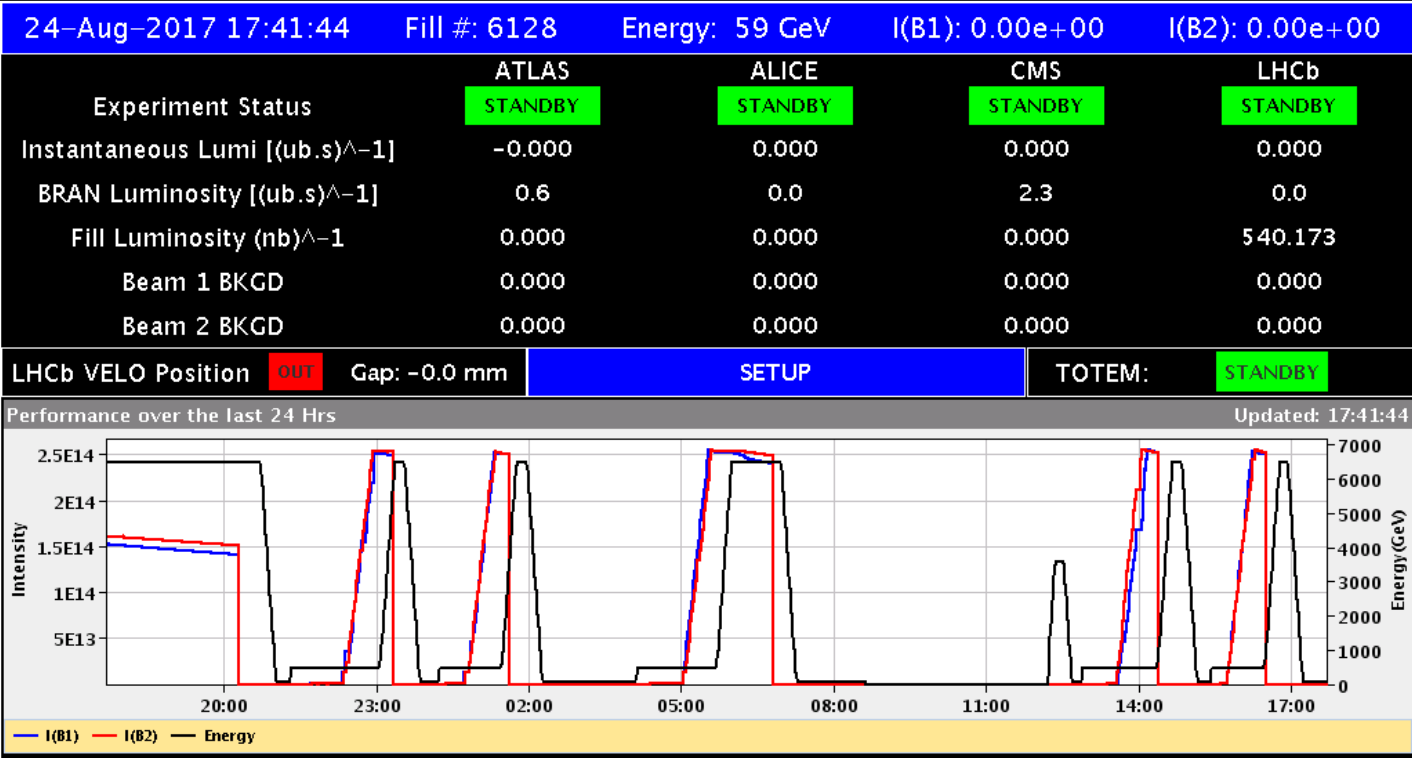


# Diagnostics using Beam Loss Monitors



# Example from Last LHC Run

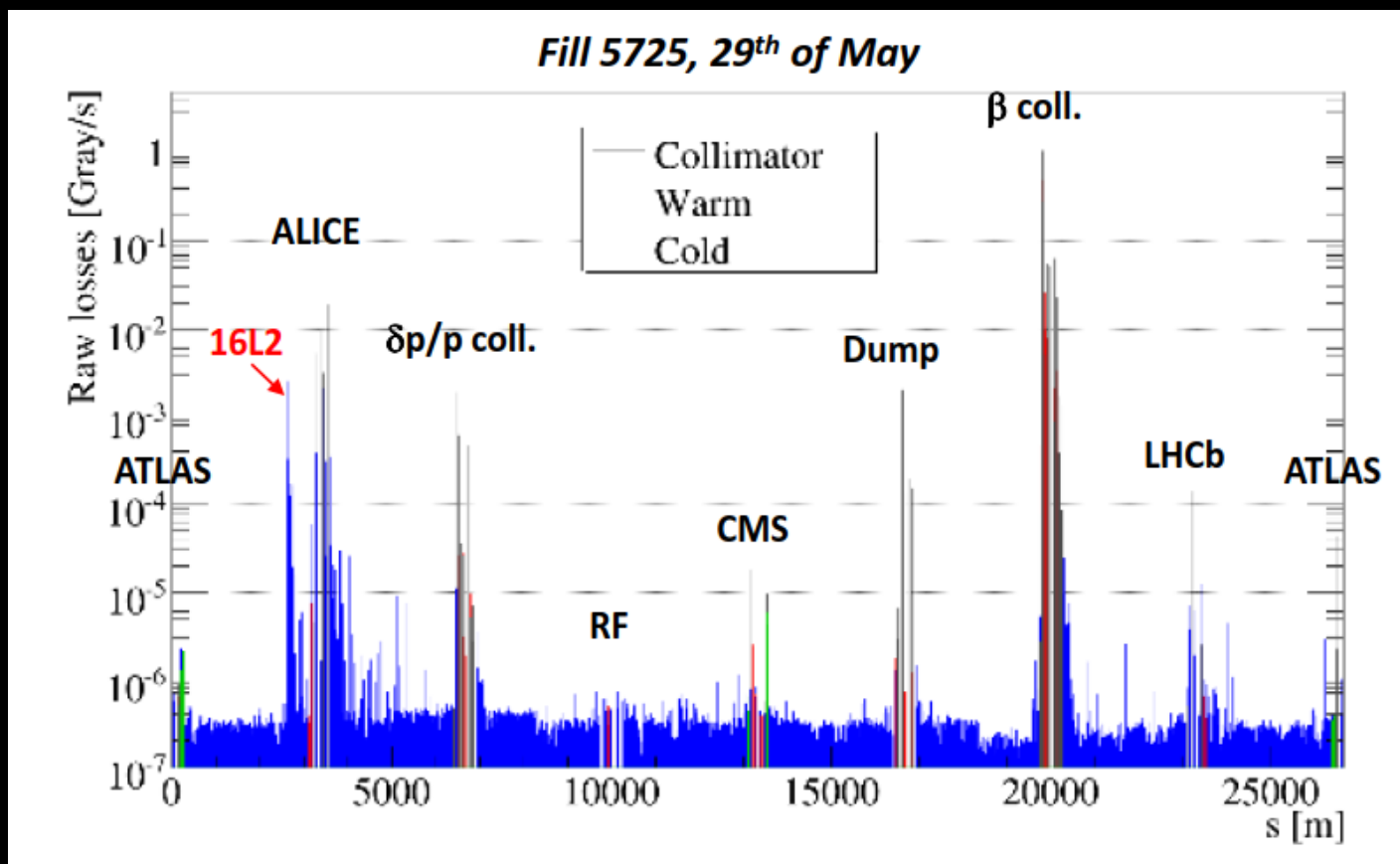
- Beam continually lost due to losses
  - What is going on?



Dump #1 5.9TeV	RF issue	Dump #2 7TeV	Dump #3 0.9TeV	Dump #4 0.8TeV
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# 16L2 – First Event

- **First beam dump event – as seen by the BLMs**
  - Local aperture measurements did not reveal evident aperture restriction
  - Clear signature of losses from both beams
    - Both beams interacting with nuclei

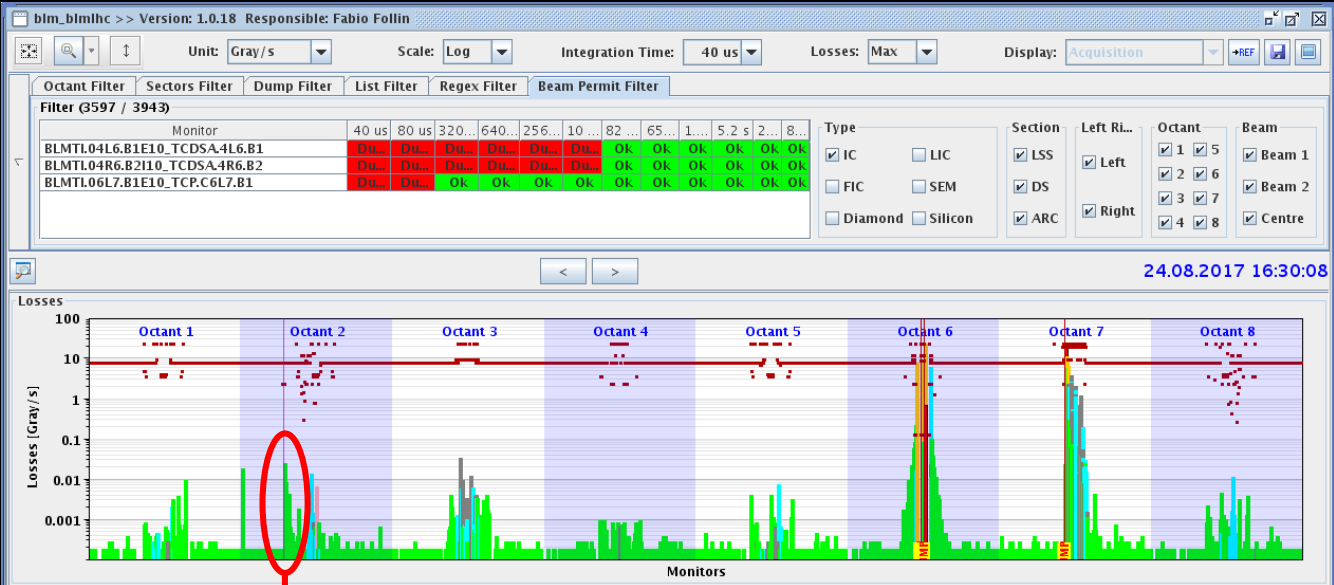






# BLM Diagnostics

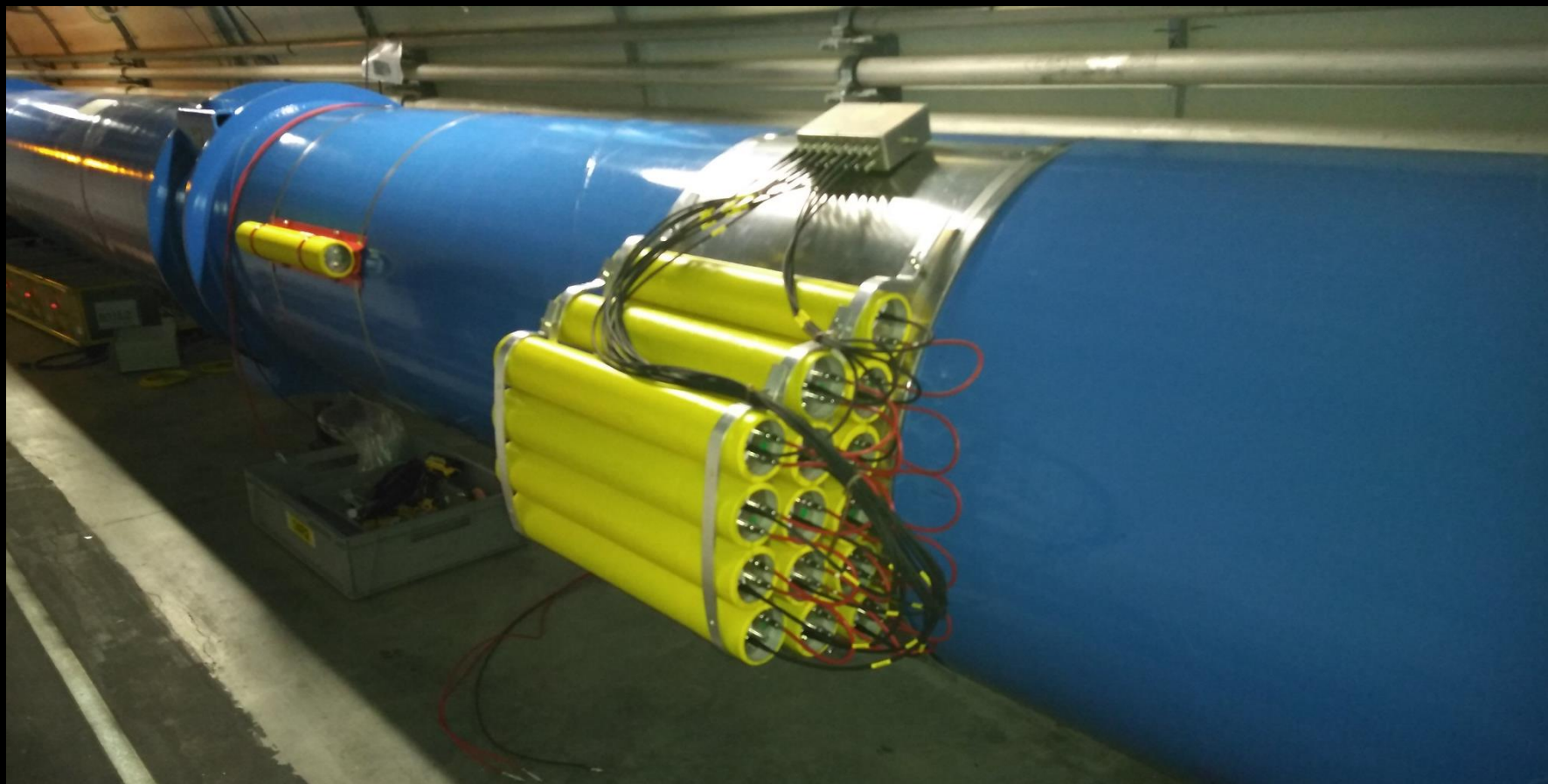
- Time evolution of Losses



# Looking for constant losses

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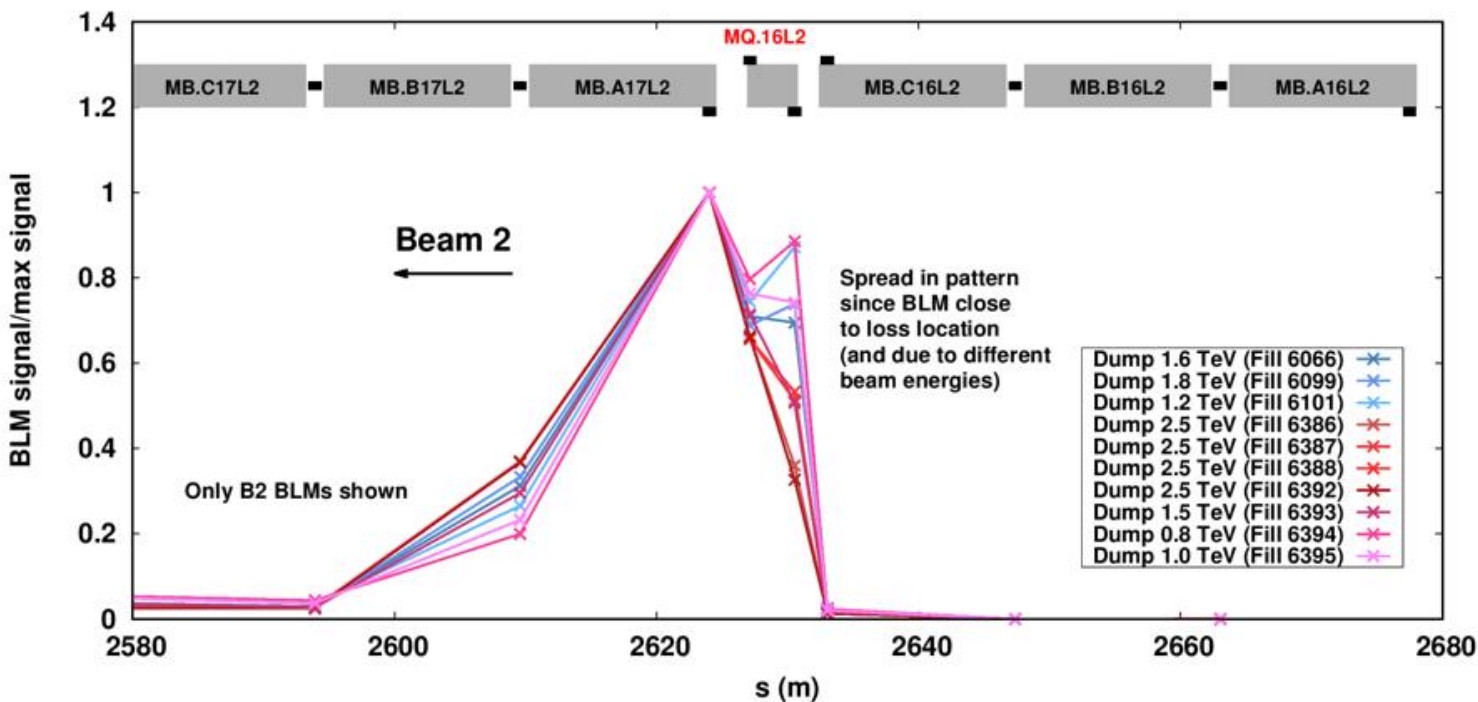
- Installation of additional BLMs!
  - Factor 15 improvement in sensitivity



# BLM Diagnostics

## • Localisation

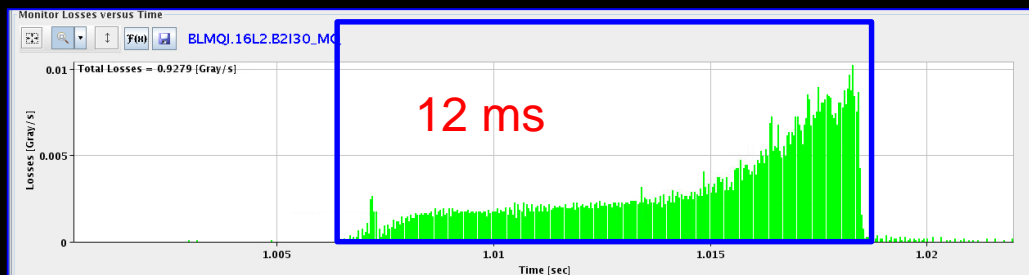
- BLM Spatial patterns clearly show losses originate from one specific interconnection
  - MQ16L2 (Cell 16 left of LHC Point 2)
  - Localisation possible to within 1m comparing with simulation
- Losses can be on either beam



# Additional Observations

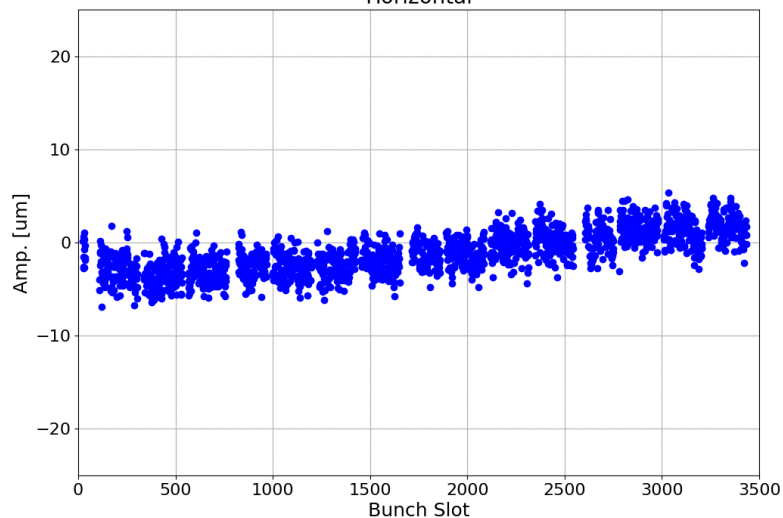
- **Beam not always dumped by BLMs in 16L2**
  - Often dumped by BLMs near primary collimators
    - Indicating development of transverse instability

Losses at BLM



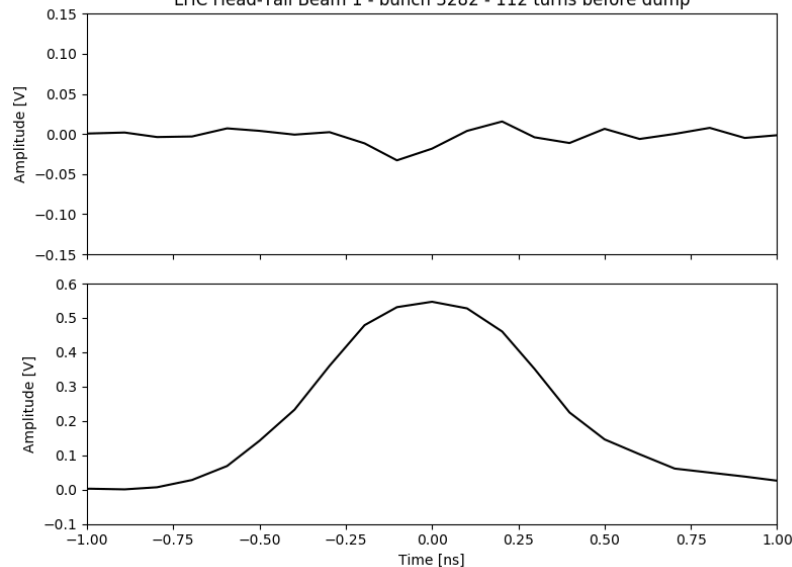
Fill: 6394, B2, Post Mortem, Turn before dump 100

Horizontal



Bunch by bunch position

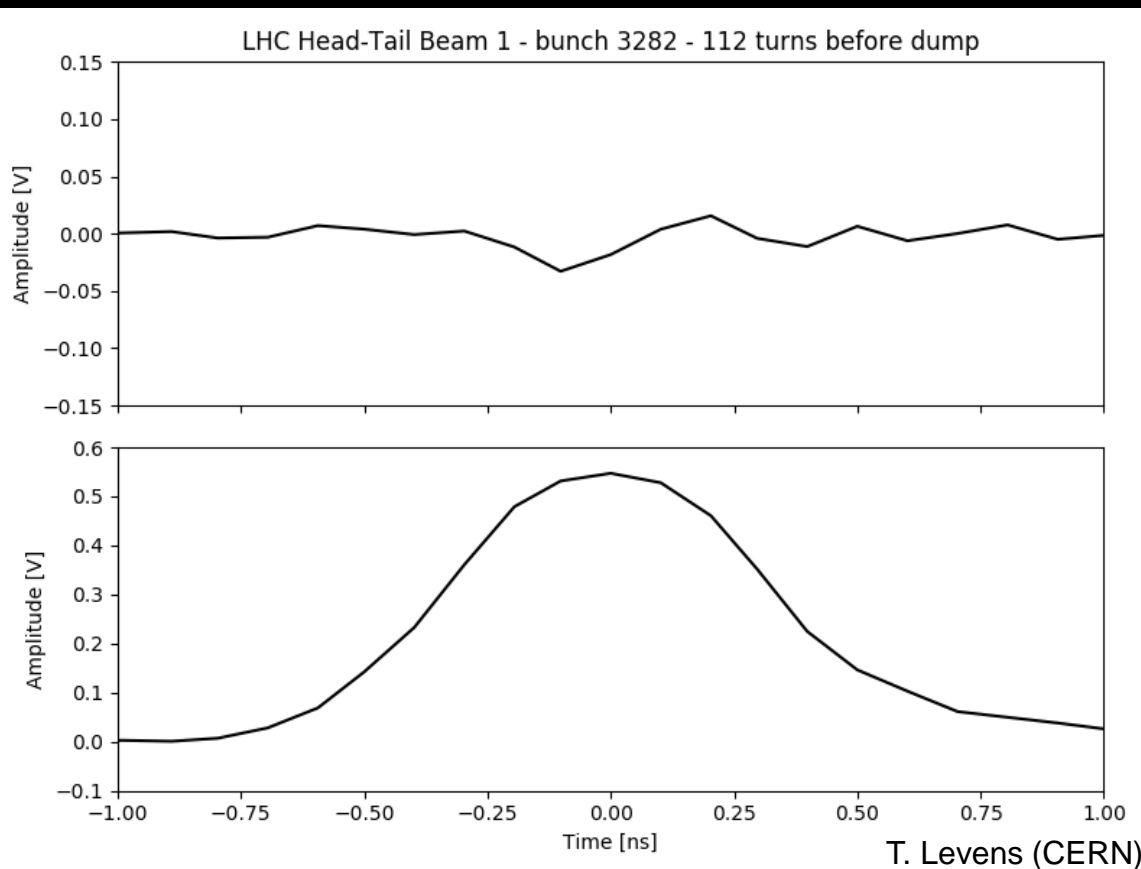
LHC Head-Tail Beam 1 - bunch 3282 - 112 turns before dump



Intra-bunch position

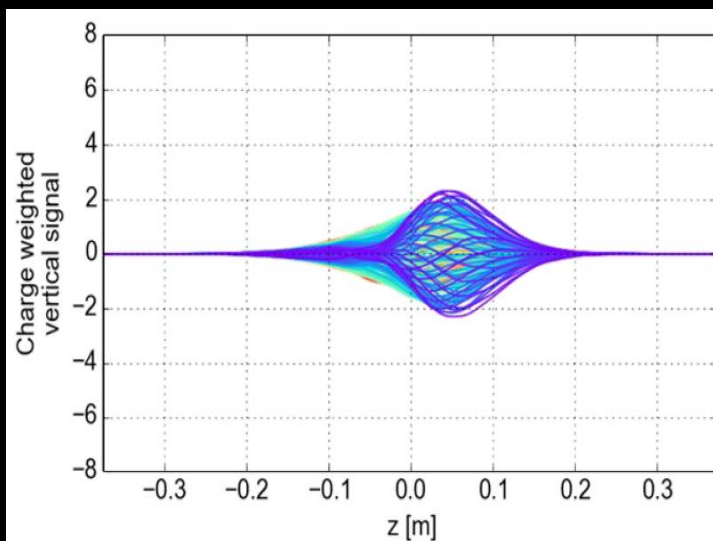
# Head-Tail Instability Monitor

- Clearly shows instability in tail of bunch
  - Allowed simulations to try and re-create similar instability
  - Achieved when considering a large density of electrons over a short distance
    - Compatible with an ionised gas cloud



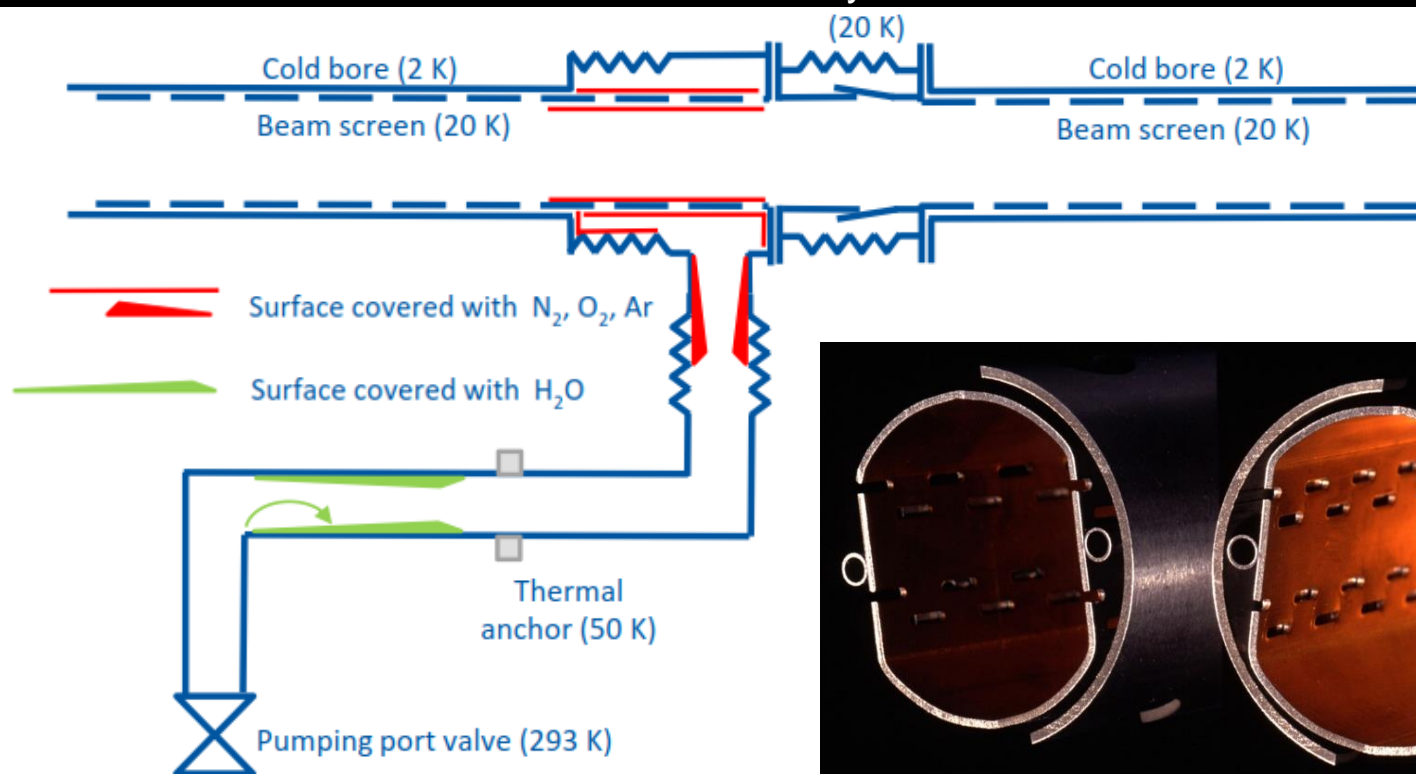
Measurement from  
head-tail monitor

Simulation

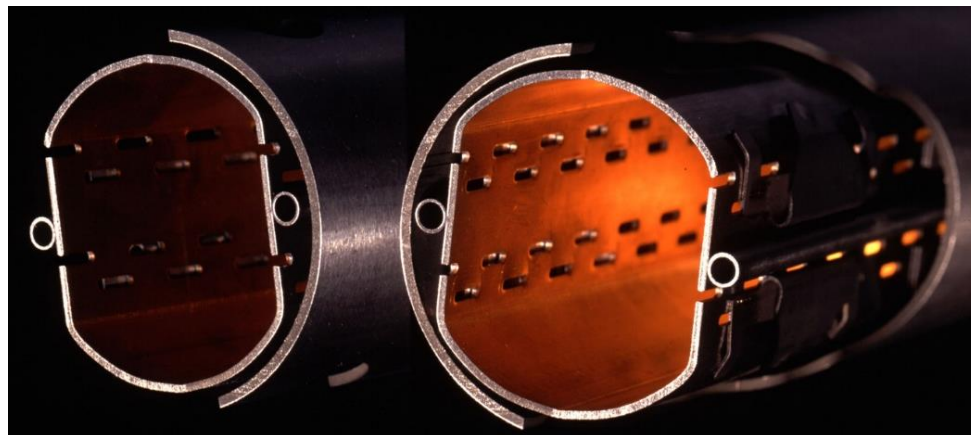


# 16L2 - Hypothesis

- **Something went wrong during vacuum pumpdown**
  - Air trapped on beam screen & cold bore of both beams
    - Solid nitrogen & oxygen formed
  - Falls into the beam & immediately vaporised
    - Creates local pressure rise with beam interaction producing ionized gas cloud
    - Leads to losses & beam instability



(same pumping group pumping beam 1 and beam 2)







# Summary of Lecture 1

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- **Today concentrated on beam position, intensity & loss monitors**
  - Went into details of how they worked
  - Gave examples of their use as diagnostic tools
- **Tomorrow we'll continue with a look at**
  - Beam profile monitoring & diagnostics
  - Tune, Coupling & Chromaticity measurement & feedback

For those that want to know more then I hope you've joined the Beam Instrumentation Afternoon Course!

- **3 Sessions on BPM design**
  - Simulation software & “hands-on” laboratory measurements
- **1 Session on Tune Measurement**
  - Simulate your own tune measurement system
- **2 Sessions on Profile Measurements**
  - “Hands-on” laboratory measurements of transverse & longitudinal profile
- **Final Session**
  - Group presentation of your BI proposals for an accelerator